## **ICSICT 2024 Technical Sessions Overview**

#### Sheraton Zhuhai Hotel, Zhuhai, China, Oct. 22 ~ Oct. 25, 2024

Date	Time	Meeting Room 1	Meeting Room 2	Meeting Room 3	Meeting Room 4	Meeting Room 5	Meeting Room 6
0.422	9:00:12:15	Tutorial Session T1 (Meeting Room 8)					
Oct.22	13:30-18:30	Tutorial Session T2 (Meeting Room 8)					
_	8:30-9:00	Opening (Grand Ball Room)					
	9:00-10:30	Keynote Session K1 (Grand Ball Room)					
	10:45-12:15	Keynote Session K2 (Grand Ball Room)					
			Session B1	Session C1	Session D1	Session E1	Session F1
Oct.23	13: 30-15: 15	Special Session	Analog Circuit I	EDA I	Novel Device I	Power Device I	Memory Device I
		the Future of AI	Session B2	Session C2	Session D2	Session E2	Session F2
	15: 30-17: 15		Analog Circuit II	EDA II	Novel Device II	Power Device II	Memory Device II
	17: 15-18: 30	Poster Session I (1st Fl.)					
	19: 00-21: 00	Reception					
	9:00-10: 30	Keynote Session K3 (Grand Ball Room)					
	10: 45-12: 15	Panel Discussion (Grand Ball Room)					
	13: 30-15: 30	Session A1	Session B3	Session C3	Session D3	Session E3	Session F3
Oct.24		AI Circuit	Analog Circuit III	RF Circuit I	Novel Device III	Power Device III	Memory Device III
	15: 30-17: 15	Session A2	Session B4	Session C4	Session D4	Session E4	Session F4
		Security	Mixed Signal I	Sensor & MEMS I	Novel Device IV	Power Device IV	Memory Device IV
	17: 15-18: 30	Poster Session II (1st Fl.)					
	9:00-10: 30	Keynote Session K4 (Grand Ball Room)					
Oct.25	10: 45-12: 15	Session A3 Digital & Memory Circuit	Session B5 Mixed Signal II	Session C5 Sensor & MEMS II	Session D5 Process I	Session E5 Reliability I	Session F5 Device Modeling I
	13: 30-15: 30	Session A4	Session B6	Session C6	Session D6	Session E6	Session F6
		Processor	Mixed Signal III	RF Circuit II	Process II	Reliability II	Device Modeling II
Ţ	15: 30-17: 15	Session A5	Session B7	Session C7	Session D7	Session E7	Session F7
		FPGA Based Design	Chip Test	Sensor & MEMS III	3D Integration	Reliability III	Device Modeling III
	19: 00-21: 00	Closing & Banquet					

# **Tutorial Session**

# **Tuesday**

### Tuesday, October 22, 9: 00 – 18: 00

Tuesday, October 22, 9: 00 – 12: 15

Meeting Room 8

**Tutorial Session T1** 

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Dr. Albert Li, Lingyange Semiconductor Inc., China

Dr. Y.K. Li, Zhuhai Fudan Innovation Institute, China

T1-1	Low-frequency Noise Characterization as a Diagnostic Tool to Characterize Advanced Semiconductor Materials and Devices
9: 00 ~10: 30	Prof. Cor Claeys, Proximus, Belgium
	Coffee Break
T1-2	Power Super-junction Devices
10: 45	Prof. Wentong Zhang, University of Electronic Science and Technology of China,
~12: 15	China

Tuesday, October 22, 13: 30 – 18: 30

Meeting Room 8

**Tutorial Session T2** 

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Dr. Yuan Li, AzurEngine Technologies Inc., China

T2-1	In-Memory Neuromorphic Computing Algorithm and Hardware		
13:30	Prof. Yufei Ma, Peking University, China		
~15:00	1101. Tuter wa, 1 exing University, China		
	Coffee Break		
T2-2	Artificial Intelligence for 6G: Implementations, Algorithms, and Optimizations		
15: 15	Prof. Chuan Zhang, Southeast University, China		
~16: 45	Froi. Chuan Zhang, Southeast University, China		
	Coffee Break		
T2-3	RF/mm-IC in silicon for wireless communication		
17: 00	Prof. Hao Gao, Eindhoven University of Technology, The Netherlands		
~18: 30	1 101. Hao Gao, Emunoven Oniversity of Technology, The Netherlands		

# **Technical Session**

### Wednesday

### Wednesday, October 23, 8: 30 -9: 00

Wednesday, October 23, 8: 30 -9: 00

Grand Ball Room

**Opening** 

Sheraton Zhuhai Hotel 1st Floor

#### Wednesday, October 23, 9: 00 –10: 30

Wednesday, October 23, 9: 00 –10: 30

Grand Ball Room

**Keynote Session K1** 

Sheraton Zhuhai Hotel 1st Floor

Session Chair: Prof. Bin Zhao, IEEE EDS, USA

K1-1	Low-Power On-Device Computation for Future AI Expansion		
9: 00 ~ 9: 45	Dr. Paul Penzes, Vice President, Qualcomm, USA		
K1-2	Effective Deep Learning Models using Medical Images for Disease Diagnosis		
9: 45 ~10: 30	Prof. Myung Hoon Sunwoo, Ajou University, Korea		
	Coffee Break		

### Wednesday, October 23, 10: 45–12: 15

Wednesday, October 23, 10: 45-12: 15

Grand Ball Room

**Keynote Session K2** 

Sheraton Zhuhai Hotel 1st Floor

Session Chair: Prof. Cor Claeys, Proximus, Belgium

K2-1	Piezotronics of the third- and fourth-generation semiconductors			
10: 45	D C 71 L' W C ' L C CT 1 1 LICA			
~11: 30	Prof. Zhong Lin Wang, Georgia Institute of Technology, USA			
K2-2	Atomic Layer Processing: Its Evolution, Diverse Applications, and Future			
K2-2	Prospects			
11: 30	Durf Fred Decrebe on Haivenity of Twente The Notherlands			
~12: 15	Prof. Fred Roozeboom, University of Twente, The Netherlands			

### Wednesday, October 23, 13: 30 – 17: 15

Wednesday, October 23, 13: 30 - 17: 15 Meeting Room 1 Special Session: the Future of AI Sheraton Zhuhai Hotel  $2^{nd}$  Floor

Session Chair: Prof. Jianguo Yang, Zhangjiang Laboratory, China

	Title			
SS-1	Transforming AI: The Impact of Computing-in-Memory on Future Technologies			
13:30 ~14:00	Tony Tae-Hyoung Kim (Nanyang Technological University, Singapore)			
SS-2	Ultra-low power multi-core hardware accelerators for AI on Edge			
14:00 ~14:30	Do Anh Tuan (A*STAR, Singapore)			
SS-3	Large language Model on Chip			
14:30 ~15:00	Hao Yu (Southern University of Science and Technology, China)			
SS-4	Progress and Challenges of Multi-physics Simulation EDA for Chiplet Packaging			
15:00 ~15:30	Wenliang Dai (Xpeedic Corp., China)			
	Coffee Break			
SS-5	Emerging Non-volatile and Non-volatile/Volatile Fused Computing-in-memory Macros for Edge Inference and Learning			
15:45 ~16:15	Chunmeng Dou (University of Chinese Academy of Sciences, China)			
SS-6	0459: Memristor Crossbar's Design Technology for Improving PPA (Power-Performance-Area) of Neural Networks			
16:15 ~16:45	Kyeong-Sik Min (Kookmin University, Korea)			
SS-7	0462: Reliability of Memristor-based Neuromorphic Computing System			
16:45 ~17:15	Michiko Inoue (Nara Institute of Science and Technology, Japan)			

Wednesday, October 23, 13: 30 - 15: 15 Meeting Room 2 **Session B1: Analog Circuit I** Sheraton Zhuhai Hotel  $2^{nd}$  Floor

Session Chair: Prof. Wenning Jiang, Fudan University, China

	Title		
B1-1	0014: Design and Verification of Low-Temperature-Drift and Capacitor-Less		
В1-1	LDO Based on 110nm Technology (invited)		
13:30	Vanagana Eu Anning Ha Thashin Wang (Laughau Univanity China)		
~14:00	Yonggang Fu, Anping He, Zhaobin Wang (Lanzhou University, China)		
B1-2	0056: A Self-adaptive Gamma Voltage Regulation Circuit for AMOLED Displays		
14:00	Zhifeng Mao, Fei Gou, Bin Sheng, Jing Xie, Wenwei Xu, Wei Liu, Jun Xu		
~14:15	(Glenfly Tech Co., Ltd., China; Tsinghua University, China)		
B1-3	0131: A Reconfigurable Thermoelectric Energy Harvesting Interface Based on		
Б1-3	OPDC and DSCT		
14:15	Peiyuan Fu, Jiabin Wang, Xufeng Liao, Lianxi Liu (Xidian University, China; Xidian		
~14:30	University Chongqing ICs Innovation Institute, China)		
B1-4	0325: A Fixed-Peak-Current Single-Inductor-MultipleOutput DC-DC Converter		
D1-4	Achieving 92.6% Peak Efficiency		
14:30	Fei Liu, Langyuan Wang, Shuyu Zhang, Hanlu Zhang, Na Yan (Fudan University,		
~14:45	China; Common Mode (GONGMO) Semiconductor Co., Ltd., China)		
B1-5	0211: Buck-Boost Converter with Stable Transition Mode for Low Average		
D1-3	Inductor Current		
14:45	Ningning Li, Yibo Zhang, Yushen Zhang, Yizhe Yang, Wenhao Yang, Yimeng Zhang,		
~15:00	Yuming Zhang (Xidian University, China)		

Wednesday, October 23, 13: 30 – 15: 15

Session C1: EDA I

Session Chair: Prof. Qi Wang, Zhuhai Fudan Innovation Institute, China

	Title			
C1-1	0281: Deep Learning Design-Flow with Static and Dynamic Optimizations (invited)			
13:30 ~14:00	Zhiqiang Que, Jose G. F. Coutinho, Wayne Luk (Imperial College London, UK)			
C1-2	0476:A New Era for Ai Processor Design Methodology with High Level Synthesis (invited)			
14:00 ~14:30	Yuan Li (XDL Technologies Inc., China)			
C1-3	0270: A QEMU-Based Virtual Platform of MPSoC			
14:30 ~14:45	Liangquan Qiao, Lei Li, Xingyu Gao, Jinxiang Wang, Fangfa Fu, Keli Long, Jinghan Zhou (Harbin Institute of Technology, China; 58th Research Institute of China Electronics Technology Group Corporation, China)			

C1-4	0193: A Parallel Harmonic Balance Method Based on GPU for Efficient Periodic
C1-4	Steady-State Analysis
14:45	Zhengzhuo Wang, Yanliang Sha, Lingyun Ouyang, Quan Chen, Jianguo Hu (Sun
~15:00	Yat-sen University, China; Southern University of Science and Technology, China)
C1 5	0245: Efficient Dynamic Memory Management for High Bandwidth Memory on
C1-5	FPGA
15:00	Varyai On Vising Mag Wanha Vin Lingli Wang (Findan University China)
~15:15	Yuwei Qu, Yiqing Mao, Wenbo Yin, Lingli Wang (Fudan University, China)

Wednesday, October 23, 13: 30 – 15: 15

Session D1: Novel Device I

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Zhengji Xu, Sun Yat-sen University, China

	Title		
D1-1	0312: Back End of Line (BEOL) Devices Using IGZO and P-type Oxides(Invited)		
13:30	John Robertson, Xuewei Zhang, Qingzhong Gui, Yuzheng Guo (Cambridge		
~14:00	University, UK; Wuhan University, China)		
D1-2	0478:Miniaturization of High-speed GaN Based Laser Diodes(Invited)		
14:00	Junfei Wang, Chaowen Guan, Leihao Sun, Zhichong Wang, Chao Shen (Fudan		
~14:30	University, China)		
D1 2	0122: Impact of Interfacial Layer on the Optoelectronic Performance of		
D1-3	MoTe <sub>2</sub> /Ge Heterojunction		
14:30	Wenyu Lei, Xiaokun Wen, Boyuan Di, Xinyue Xu, Haixin Chang, Wenfeng Zhang		
~14:45	(Huazhong University of Science and Technology, China)		
D1-4	0098: MoS2-WS2 Heterostructure-enabled Optoelectronic Synaptic Diode		
14:45	Mingjie Li, Yingtao Ding, Jianzhi Hu, Hankun Zhao, Yilin Sun (Beijing Institute of		
~15:00	Technology, China)		
D1-5	0472: Pseudo-Parallel Symmetrical and Crossed Perovskite Solar Cells for		
D1-9	Bifacial Applications		
15:00	Guang-Wei Huang, Hsing-Mao Cheng, Jyi-Tsong Lin (Sun Yat-Sen University,		
~15:15	Taiwan, China)		

Wednesday, October 23, 13: 30 – 15: 15

Session E1: Power Device I

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Shaofeng Yu, Fudan University, China

	Title		
E1-1	0282: Gate Driver ICs for Wide Bandgap Power Transistors (invited)		
13:30	Wai Tung Ng, Rophina Li, Wentao Cui, Jingyuan Liang (University of Toronto,		
~14:00	Canada)		
E1-2	0291: Suppression of Back-Gating Effect by Integrated Substrate Termination		
E1-2	Network for 200V Monolithic GaN Half-Bridge Power IC		
14:00	Mengyao Zhao, Yifei Zheng, Yanfeng Ma, Yuan Sun, Denggui Wang, Chuanqi Pan,		
~14:00	Jianjun Zhou, Sheng Li, Siyang Liu, Long Zhang, Weifeng Sun (Southeast University,		
~14.13	China)		
E1-3	0326: High Short-Circuit Capability and Low-Loss SOI-LIGBT with		
E1-3	Double-Integrated NMOS		
14:15	Jialei Tan, Jie Wei, Jinlong Lu, Xindi Liu, Gaoqiang Deng, Wei Song, Pei Guo, Bo		
~14:30	Zhang, Xiaorong Luo (University of Electronic Science and Technology of China,		
717.50	China; Chengdu University of Information Technology, China)		
E1-4	0328: Body Diode Degradation Mechanism Of 1200V SIC Power MOSFETs		
121-4	Under Gamma Rays Total Ionizing Dose Irradiation		
14:30	Yu Tian, Zhaoxu Song, Hao Fu, Jiaxing Wei, Siyang Liu, Weifeng Sun (Southeast		
~14:45	University, China)		
E1-5	0361: Novel Heterojunction Field Plate β -Ga2O3 MOSFET with High		
E1-3	Breakdown Voltage		
14:45	Xiangnan Li, Jie Wei, Kai Zhao, Linyao Hao, Xiaosong Peng, Yuxi Wei, Renkuan Liu,		
~15:00	Wei Song, Pei Guo, Xiaorong Luo (University of Electronic Science and Technology		
~13.00	of China, China; Chengdu University of Information Technology, China)		

Wednesday, October 23, 13: 30 – 15: 15

Session F1: Memory Device I

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Jian Huang, Sun Yat-sen University, China

	Title		
F1-1	0010: Sub-nanosecond Operation Speeds of Ferroelectric Domain Wall Memory		
F 1-1	(Invited)		
13:30	An array Lines (E. Jan Hairannita China)		
~14:00	Anquan Jiang (Fudan University, China)		
F1-2	0096: Optimizing Flash Memory Towards Storage-Class Memory (SCM)		
F 1-2	Applications (Invited)		
14:00	Xinyi Guo, Yang Feng, Jing Liu, Junyu Zhang, Xuepeng Zhan, Jixuan Wu, Jiezhi		
~14:30	Chen (Shandong University, China; Institute of Microelectronics of Chinese Academy		

	of Sciences, China; Neumem Co., Ltd, China)
F1-3	0020: Investigation of Reliability Characteristics of Hf <sub>x</sub> Zr <sub>1-x</sub> O <sub>2</sub> -Based FeFET and
F1-3	AFeFET Non-Volatile Memory
	Min Liao, Xianzhou Shao, Junshuai Chai, Xiaoqing Sun, Xiaoyu Ke, Hao Xu, Jinjuan
14:30	Xiang, Xiaolei Wang, and Wenwu Wang (Institute of Microelectronics, Chinese
~14:45	Academy of Sciences, China; Beijing Superstring Academy of Memory Technology,
	China)
F1-4	0066: Deep Understanding of Charge Trapping Phenomenon in n-FeFET and
r 1-4	Endurance Improvement by Interlayer Engineering
14:45	Saifei Dai, Hao Xu, Fengbin Tian, Xianzhou Shao, Xiaoqing Sun, Junshuai Chai,
14:45 ~15:00	Xiaolei Wang, Wenwu Wang (Institute of Microelectronics, Chinese Academy of
~13.00	Sciences, China; University of Chinese Academy of Sciences, China)
F1-5	0407: An FPGA-based Dual-mode SSD for Device-side Performance
	Optimization
	Xingyu Chen, Sirui Peng, Hankun Lv, Zhangbin Yang, Daixiao Peng, Xi Cai,
15:00	Xueguang Lian, Yong Ding, Xiaoyong Xue (Fudan University, China; University of
~15:15	Chinese Academy of Sciences, China; Institute of Electrical Engineering, Chinese
~13.13	Academy of Sciences, China; China Three Gorges Construction Engineering
	Corporation, China; Zhejiang University, China)
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## Wednesday, October 23, 15: 30-17: 15

Wednesday, October 23, 15: 30-17: 15

Meeting Room

2

**Session B2: Analog Circuit II** 

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Wenning Jiang, Fudan University, China

	Title
B2-1	0152: Dual-Loop Reference-less CDR with HLD for Wide Lock-in Range
	(invited)
15:30	Chua-Chin Wang (Sun Yat-Sen University, Taiwan, China)
~16:00	Chua-Chini Wang (Sun Tui-Sen University, Tuiwan, China)
B2-2	0089: A SET Sensitive Model of LC and Ring Voltage Controlled Oscillator in
B2-2	FinFET Technology
16:00	Liu Heyuan, Yuan Hengzhou, Lu Jianzhuang, Chen Xiaowen, Sang Hao, Liu Jingtian,
~16:15	Guo Yang (National University of Defense Technology, China; Academy of Military
~10:13	Sciences PLA China, China)
B2-3	0093: A Low Spur Wideband PLL in 65nm CMOS
16:15	Zijun Wang, Biao Li, Teng Wang, Hong Li, Ruiting Niu, Jinpeng Lin (Space Star

~16:30	Technology Limited Corporation, China)
B2-4	0217: A Low Power PLL Circuit with Signal 50% Duty Cycle Corrected in
D2-4	180nm CMOS
16:30	Bangtian Li, Xueke Li, Liying Chen, Chuantong Cheng (Tiangong University, China;
~16:45	Institute of Semiconductors, Chinese Academy of Sciences, China)
B2-5	0156: MTJ based Compensation for Charge Pump Temperature Drift
16:45	Yongliang Zhou, Jingxue Zhong, Chengxing Dai, Yingxue Sun, Xin Li, Chunyu Peng
~17:00	(Anhui University, China; Anhui Anxin Electronic Technology Co., Ltd, China)
B2-6	0213: A 112-Gb/s Coherent Receiver with a Novel Modulation Format
17:00	Tianyuan Zhong, Boyang Zhang, Weixin Gai (Peking University, China; Beijing
~17:15	Advanced Innovation Center for Integrated Circuits, China)

Wednesday, October 23, 15: 30-17: 15

Session C2: EDA II

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Qi Wang, Zhuhai Fudan Innovation Institute, China

	Title
C2-1	0292:An Improved Clock-Aware Global Placement Algorithm (invited)
15:30	Zione Co Dinazione Zhana (Chana haita ah Haita a
~15:55	Ziang Ge, Pingqiang Zhou (Shanghaitech University, China)
C2-2	0411: Analyzing Timing in Shorter Time: A Journey through Heterogeneous
C2-2	Parallelism for Static Timing Analysis (invited)
15:55	Zizhana Cua Viha Lin Bunghana Wana Bu Huana (Bakina University China)
~16:20	Zizheng Guo, Yibo Lin, Runsheng Wang, Ru Huang (Peking University, China)
C2-3	0216: TBPart-b: An Effective Hypergraph Partitioning Algorithm Considering
C2-3	Topological Order Balance for Processor-based Hardware Emulation
16:20	Jing Tang, Shunyang Bi, Hailong You (Xidian University, China)
~16:34	Jing Tang, Shunyang Bi, Hanong Tou (Atutan University, China)
C2-4	0068: FCE: A Fast CGRA Architecture Exploration Framework
16:34	Sichao Chen, Yiqing Mao, Yuan Dai, Xuchen Gao, Wai-Shing Luk, Wenbo Yin, Lingli
~16:48	Wang (Fudan University, China)
C2-5	0179: Research on Parametric Subthreshold Cell Delay Modeling Based on ANN
16:48	Xuelian Zhang, Yuping Wu, Zhiqiang Li, Donglin Liu, Shushan Qiao
	(Institute of Microelectronics of Chinese Academy of Sciences, China; University of
~17:02	Chinese Academy of Sciences, China)
C2-6	0393: A High-Performance Routing Architecture with 16 LUTs per CLB for

	Nanoscale FPGAs
17:02	Sijing Yang, Jide Zhang, Hao Zhou, Lingli Wang (Fudan University, China)
~17:15	Sijing rang, Jue Zhang, Hao Zhou, Lingii wang (Fudan University, China)

Wednesday, October 23, 15: 30-17: 15

Session D2: Novel Device II

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chaire Prof. Zhongii Vy. Sur Vet can University. China

Session Chair: Prof. Zhengji Xu, Sun Yat-sen University, China

	Title
D2-1	0450: Cryogenic and RF Modeling of On-Chip Passive Devices for Quantum
	Computer (Invited)
15:30	Aline Tenchine (The Hair queit, of Chien Hair queit, Lunga)
~16:00	Akira Tsuchiya (The University of Shiga University, Japan)
D2-2	0457: Ferroelectric Transistors Based on Two Dimensional Materials (Invited)
16:00	Warner Li (E. Januaria China)
~16:30	Wenwu Li (Fudan university, China)
D2-3	0473: Comparison of Nanosheet and Fin Integration in Stacked Induced Tunnel
D2-3	Field-Effect Transistors
16:30	Ruei-Cheng Tu, Chia-Yo Kuo, Jyi-Tsong Lin (Sun Yat-Sen University, Taiwan, China)
~16:45	Ruet-Cheng Tu, Chia- 10 Ruo, Jyi- Isong Lin (Sun Tut-Sen University, Tutwan, China)
D2-4	0160: Nonlinear Contact Behavior in MoS2 Field Effect Transistors at Cryogenic
D2-4	Temperature
16:45	Shihab Ahammed, Mansun Chan (The Hong Kong University of Science and
~17:00	Technology, Hong Kong, China)
D2-5	0158: Experimental Verification of 1D Transport Model by Quantized Current
D2-5	Spectrum of Si JNT Device
17:00	Zi-Meng Shang, Bo-Wei Wang, Wei-Hua Han (Institute of Semiconductors, Chinese
~17:15	Academy of Sciences, China; University of Chinese Academy of Sciences, China)

Wednesday, October 23, 15: 30-17: 15

Session E2: Power Device II

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Shaofeng Yu, Fudan University, China

	Title
E2-1	0401: Investigation of SiON Passivation for High Performance AlGaN/GaN
	HEMTs (invited)
15:30	Difei Fan, Chenkai Deng, Jiming Zhang, Peiran Wang, Nick Tao, Qing Wang,
~16:00	Hongyu Yu (Southern University of Science and Technology, China; Maxscend

	Microelectronics Company Limited, China)
E2-2	0009: 180nm BCD Technology Platform with 8V to 65V Isolated LDMOS
	Qi Ding, Renxiong Li, Ning Ning, Jun Huang, Yutuo Guo, Yu Wang, Kunqin He,
16:00	Yaxin Li, Huaishan Wang, Juan Tang, Qiuyue Huo, Minghong Yuan, Pan Peng, Ming
~16:15	Qiao, Lulu Peng, Bo Zhang (United Microelectronics Center Co., Ltd, China;
	University of Electronic Science and Technology of China, China;)
E2-3	0200: A Novel Insulated Gate-Triggered Thyristor with Integrated Super-Clamp
E2-3	Gate Transient Voltage Suppressor for Ultrahigh di/dt Pulse Switching
16:15	Shiyu Deng, Yuxiao Yang, Xinqi Sun, Pengwei Zhou, Ruize Sun, Chao Liu, Wanjun
~16:30	Chen, Bo Zhang (University of Electronic Science and Technology of China, China)
E2-4	0210: Device Instability in the Third Quadrant of Schottky-Type p-GaN Gate
122-4	HEMTs: The Hole Defficiency & Trapping Effect
16:30	Kuangli Chen, Shuting Huang, Jinggui Zhou, Ning Yang, Jianggen Zhu, Enchuan
~16:45	Duan, Bo Zhang, Qi Zhou (University of Electronic Science and Technology of China
~10.43	(UESTC), China)
	0226. Static Characteristic Decourse Of Sic MOSEFTs Induced By Dynamic
E2-5	0236: Static Characteristic Recovery Of SiC MOSFETs Induced By Dynamic Gate Stress After Total Ionizing Dose Irradiation
16:45	Jiahao Hu, Xiaochuan Deng, Xing Zeng, Tao Xu, Haibo Wu, Xuan Li, Bo Zhang
~17:00	(University of Electronic Science and Technology of China, China)
~17:00	(Oniversity of Electronic Science and Technology of China, China)

Wednesday, October 23, 15: 30-17: 15

Meeting Room

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Session F2: Memory Device II
Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Jian Huang, Sun Yat-sen University, China

	Title
F2-1	0141: A Simulation Comparison of Channel-All-Around and Gate-All-Around 3D
	Vertical Structure FeFET with IGZO Channel
	Xuebin Wang, Zhijian Guo, Yutao Li, Chengji Jin, Jixuan Wu, Guanhua Yang,
15:30	Yuanxiao Ma, Masaharu Kobayashi, Fei Mo, Yeliang Wang (Beijing Institute of
1 2 10 1	Technology, China; The University of Tokyo, Japan; Institute of Microelectronics,
~15:45	Chinese Academy of Sciences, China; Shandong University, China; Xidian University,
	China)
F2-2	0174: Low Operating Voltage in HfO2/ZrO2 Superlattice Ferroelectric Capacitor
F 2-2	Achieved by Thickness Scaling
15.45	Dongya Li, Huan Liu, Peiyuan Du, Fei Yu, Chengji Jin, Xiao Yu, Yan Liu, Genquan
15:45	Han, Yue Hao (Xidian University, China; Zhejiang Lab, China; Hangzhou Institute of
~16:00	Technology, Xidian University, China)
F2-3	0257: Co-optimization of Oxide Semiconductor-based Ferroelectric Transistors

	Between Electrical Performance and Ambient Stability By Using TiO2-IGZO
	<b>Dual-Channel Layers</b>
16:00	Shangze Li, Xujin Song, Dijiang Sun, Xiaoyan Liu, Jinfeng Kang (Peking University,
~16:15	China)
F2-4	0340: Enhancing Computational Precision in PLRAM-based In-memory
	Computing with High-Low Bit Concatenation
16:15	Saike Zhu, Xiang Qiu, Yong Gong, Cimang Lu, Yi Zhao (Zhejiang University, China;
~16:30	China Nanhu Academy of Electronics and Information Technology, China; East China
10.30	Normal University, China; Flash Billion Semiconductor Co. Ltd., China)
F2-5	0062: FeFET based Logic-in-Memory Pipeline-Style Circuits
16:30	Yang Li, Zhaohui Yang, Yinshui Xia (Ningbo University, China)
~16:45	Talig Li, Zhaohui Talig, Thishui Ala (ivingbo University, China)
F2-6	0172: Study of Vth Degradation Mechanism in FeFET with
r 2-0	TiN/Al <sub>2</sub> O <sub>3</sub> /HfO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> /Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> /SiO <sub>x</sub> /Si Structure
	Runhao Han, Jia Yang, Tao Hu, Mingkai Bai, Yajing Ding, Xianzhou Shao, Saifei Dai,
16:45	Xiaoqing Sun, Junshuai Chai, Hao Xu, Kai Han, Xiaolei Wang, Wenwu Wang,
~17:00	Tianchun Ye (Institute of Microelectronics, Chinese Academy of Sciences, China;
	University of Chinese Academy of Sciences, China; Weifang University, China)
E2 7	0189: Random Number Generation from 3D-NAND Flash Memory Using
F2-7	Shallow Charge Trap Related Short-Term Retention Errors
17:00	Ruibin Zhou, Jian Huang, Xianping Liu, Yuhan Wang, Xinrui Zhang, Yungen Peng,
~17:15	and Zhiyi Yu (Sun Yat-sen University, China; Peng Cheng Laboratory, China)

# Wednesday, October 23, 17: 30 – 18: 30

Wednesday, October 23, 17: 30 –18: 30

**Poster Session I** Sheraton Zhuhai Hotel 1<sup>st</sup> Floor

	Title
P1-1	0007: A Fast-Response Current Source with High Impedance for
F 1-1	Zero-Crossing-Based Circuits
	Ruoyu Li, Xianglong Wang, Jianqiang Xu, Yintang Yang (Xidian University, China)
P1-2	0028: Design of 12-bit Low-Power Single-Slope ADC with 2048 Columns for
P1-2	Infrared Focal Plane Array
	Lixiang Han, Hao Li, Yihui Zhang, Liang Gao, Dongsheng Liu (Huazhong University
	of Science and Technology, China; Hubei Optics Valley Laborator, China; )
P1-3	0040: A Low Power Narrow-Band Complex-Bandpass Filter Based on

	Feedforward Compensation Amplifiers for NB-IoT Applications
	Xu Zhao, Ziqiang Wang, Jie Gan (Beijing Smart-chip Microelectronics Technology
	Co.,Ltd, China; Tsinghua University ,China)
P1-4	0069: A 12V to 1V Tri-state DSD Hybrid Converter by Self-Balanced Dual Flying Capacitors with 0.3mV Output Ripple and 90.09% Peak Efficiency
	Yixing Wang, Qianhui Liu, Yuhua Chen, Yizhe Yang, Yimeng Zhang, Yuming Zhang
	(Xidian University, China;)
P1-5	0077: A Multi-Phase Clock Self-Calibrating Circuit
	Zhihuai Li, Li Jiang, Xueming Wei, Zilu Cai, Jiami Tang (Guilin University of
	Electronic, China)
P1-6	0090: A 18V, 600mA Load Current, 22MHz High-Voltage Power Amplifier with
	Over-Temperature Protection and Bidirection Enable Logic
	Yuan Ren , Xin'an Wang (Peking University, China)
	0153: A 10-MHz Four-Phase Hysteretic Control DC-DC Converter with Inductor
P1-7	Current Self-balancing
	Yushen Zhang, Yibo Zhang, Yizhe Yang, Ningning Li, Wenhao Yang, Yimeng Zhang,
	Yuming Zhang (Xidian University, China)
	0227. A High Presision, 40 9C to 150 9C Dandgan Defenence with Duel
P1-8	0227: A High Precision -40 °C to 150 °C Bandgap Reference with Dual Temperature Compensation
	Yuhan Zhang, Jianzheng Li, Xiaomeng An, Lina Wang, Yajie Qin (Fudan University,
	China)
P1-9	0241: A Biphasic Neural Stimulator with Adaptive Pulse-Width Modulation Charge Balancer
	Hailong Tang, Wenxian Gu, Yifan Song, Hengchang Bi, Xing Wu, Liangjian Lyu
	(East China Normal University, China)
P1-10	0250: A PPG Analog Front-End With PVT-Insensitive High-Pass Frequency
	Zhaofeng Huang, Zepeng Huang, Hengchang Bi, Xing Wu, Liangjian Lyu (East
	China Normal University, China)
P1-11	0330: A Fully integrated FVF based low-noise voltage buffer for ADC reference
	Ikhwan Kim, Yajie Qin (Fudan University, China)
P1-12	0387: A Resistor-Free Grounded High-Frequency Memristor Emulator
	Xinying Su, Bingjun Xiong, Junjie Yu and Jingjing Liu (Sun Yat-Sen University,
	China)
	0027: An Ultra-Low-Leakage Current Sensing Interface for Wide Temperature
P1-13	Range

	Jinsheng Tang, Chun Zhao, Lin He (Nanjing University of Posts and
	Telecommunications, China)
	0029: A Global Threshold Voltage Finder Technology for the Readout Circuit of
P1-14	
	Event-based Vision Sensor
	Yanwen Su, Hao Li, Dongsheng Liu, Ang Hu, Kaiyue Li (Huazhong University of
	Science and Technology, China; Hubei Optics Valley Laboratory, China)
	0107: A Residue Amplifier With 72.27 dB Loop-Gain and 4.64 GHz Closed
P1-15	Loop Bandwidth consuming 6.4 mW for 12-Bit 1-Gsps Pipelined ADC
	Jiangbo Wei, Jin Liu, Wei Tian, Chao Wang, Maliang Liu (Xi'an Microelectronics
	Technology Institute, China; Xidian University, China)
	0124: A 180 mV-1.6 V Thermoelectric Energy Harvesting Converter with
P1-16	Low-Voltage Cold Start and Less than 1 µW Power Loss
	Chunlin Wang, Anzhi Yan, Tianyu Guo, Peng Wan, Houfang Liu, Yi Yang, Tianling
	Ren (Tsinghua University, China)
P1-17	0150: A Signal Conditioning ASIC With High Precision and Low Noise for
11-17	MEMS Accelerometers
	Quan Sun, Rui Liu, Zhe Zheng, Lei Dong, Ji-jiang Wang (Xi 'an Aerosemi Technology.
	Co., Ltd., China; Beijing Smart-chip Microelectronics Technology Co., China)
	0185: Design of a high-precision self-calibration readout circuit for CMOS
P1-18	microbolometer
	Qianhao Zhang, Jie Liu, Sheng Xu, Yiming Liao, Feng Yan, Xiaoli Ji (Nanjing
	University, China; Nanjing University of Science and Technology, China)
	Oniversity, China, Manjing Oniversity of Science and Technology, China)
	0297: A High-precision Current Detection Circuit for Battery Management
P1-19	System
	Yue Shi, Shi-dong Wang, Zekun Zhou, Bo Zhang, Zhigang Qin (University of
	Electronic Science and Technology of China, China; Chengdu University of
	Information Technology, China; Saitama Institute of Technology, Japan)
P1-20	0327: A High-Voltage Smooth Self-Starting Reference Current Source Circuit
	Dongyan Zhao, Jie Pa, Chenghao Zhang, Yidong Yuan, Yi Hu, Hongwei Shen, Zekun
	Zhou, Member, IEEE (Beijing Smart-chip Microelectronics Technology Co., Ltd.,
	China; University of Electronic Science and Technology of China, China)
	2, 2
	0276: A Temporal and Spatial Reuse Interpolation Hardware for VVC Motion
P1-21	
	Compensation
	THE STREET STREET
	Huanxiang He, Shushi Chen, Leilei Huang, Yibo Fan (Fudan University, China)
P1-22	Huanxiang He, Shushi Chen, Leilei Huang, Yibo Fan (Fudan University, China)  0293: A Broadband Digital Beamforming Method Based on FPGA

P1-23	0305: Conditional cycle termination RANSAC
	Tong Jiang, Yujie Huang, Liyuan Peng, Mingyu Wang, Wenhong Li, Minge Jing,
	Xiaoyang Zeng (Fudan University, China; Shanghai ExploreX Technology Co., Ltd.,
	China)
P1-24	0371: A multi-resolution propagation algorithm and pixel grouping storage
	strategy for PatchMatch Stereo
	Kai Liu, Zhenyu Zhang, Haiwei Wang, Leilei Huang, Chunqi Shi, Long Xu, Runxi
	Zhang (East China Normal University, China)
P1-25	0378: An XOR Arbiter PUF based on the IGZO TFT Devices
11-23	Xiang Chen, Yongliang Chen, Xiaole Cui (Peking University Shenzhen Graduate
	School, China)
D1 24	0052: Design and Implementation of Hierarchical Storage Structure for
P1-26	MCCSIP-RAA
	Longmei Nan, Yu Jin, Yiran Du, Tao Chen, Yanjiang Liu, Wei Li (Institute of
	Information Science and Technology, China)
P1-27	0242: A Highly Scalable Hardware HEVC Encoder Based on FPGA
	Guohao Xu, Chenlong He, Shiyan Yi, Leilei Huang, Xiaoyang Zeng, Yibo Fan (Fudan
	University, China; East China Normal University, China)
P1-28	0259: A Hardware-friendly Fast Block Partition Decision Algorithm Based on Histogram of Oriented Gradient for AV1
	Guohao Xu, Shiyan Yi, Zhijian Hao, Leilei Huang, Hao Zhang, Xiaoyang Zeng, Yibo
	Fan (Fudan University, China; East China Normal University, China)
	Tank (2 main emirerally), emina, 2 mir emina 1 eminerally, emina,
P1-30	0391: A High-Performance MTJ-LUT Circuit Using 4T1M Architecture
	Yu Pan, Yuejun Zhang, Shuaicheng Guo, Yuanxin Tian, Bo Hong, Rui Fang, Liang
	Wen (Ningbo University, China; China Coast Guard Academy, China)
P1-31	0261: Optimizing Communication Effciency of GNN Inference in Distributed
	System
	Wenqian Zhou, Qiaosha Zou (Fudan University, China; Zhejiang Lab, China)
	0205, CCT, Cinculie of Course Time Transfer
P1-32	0295: SST: Simplified Space-Time Transformer based on Time-assisted Spatial MSA for 3D Human Pose Estimation
	Sheng Lu, Qiyun Dong, Zhenyin Zhang, Gengsheng Chen, Yinna Zhu, Wei Xu (Fudan
	University, China; Jiashan Fudan Institute, China)
	Chronony, China, Gushan Luain Listiano, China)
	0173: SALTS: An Efficient and Flexible Self-Attention Accelerator with Long
P1-33	Token Support on FPGA
	Kaiqi Chen, Xinhua Shi, Jun Han (Fudan University, China)

P1-34	0222: RISC-V Neural Network Instruction Design and Simulation with Cache Scheduling via ROCC Interface
	Siyao Dai, Zikang Zhou, Jun Han (Fudan University, China)
P1-35	0226: Impact of external magnetic interference on the performance of MRAM-based neuromorphic computing
	Yingtong He, Suihuan An, Yu Chen, Xue Zhou, Xihui Yuan, Weidong Zhang, Zheng
	Chai, Tai Min (Xi'an Jiaotong University, China; Liverpool John Moores University,
	UK)
P1-36	0375: A Hardware Accelerator for Image Super Resolution with Algorithm
11-30	Lightweighting and Custom Fusion Engine
	Menghan Li, Sheng Lu, Jun Han (Fudan University, China)
	0268: Hardware Implementation of High Speed Fault Tolerant Parallel
P1-37	Accelerator
	Wenzhe Ma, Wenzhe Ma (Fudan University, China)
P1-38	0349: Composite Filter-based Bicubic Interpolation Method and FPGA Implementation
	Li Zhang, Jingjing Liu, Yujie Zhu, Jianhua Zhang (Shanghai University, China)
P1-39	0157: MTJ based Temperature Tracking Read/Write Assist for High Speed SRAM Bitcell
	Yongliang Zhou, Chengxing Dai, Jingxue Zhong, Yingxue Sun, Xin Li, Chunyu Peng
	(Anhui University, China; Anhui Anxin Electronic Technology Co., Ltd, China)
P1-40	0353: System-level Evaluation of AOS Gain Cell eDRAMs for Low-power Normally-off Computing
	Long Chen, Yecheng Yang, Wei Li, and Shao Hao Wang (Fuzhou University, China)
P1-41	0024: A High Sigma Monte Carlo Analysis Solution Via Machine Learning for SRAM Margin Signoff
	Amy Rao (EBA Center, China)
P1-42	0138: Enhanced Multi-bit Computation using CIM SRAM Technology
	Ruiyong Zhao, Yibo Hu, Zhipeng Ren, Yizhe Yin, Jing Chen (Shanghai Institute of
	Microsystem and Information Technology, China)
P1-43	0045: A Compute-in-Memory Macro Based on Complementary 2T2C FeRAM Cell for BNNs
	Jinyu Li, Mingzhang Xie, Shisheng Xiong (Fudan University, China; China Resources Microelectronics Co., Ltd., China)

P1-44	0057: A Novel High Speed Low Power Differential Circuit-Based FRAM Read Scheme
	Qiuyu Tao, Jiabao Ye, Xuecheng Cui, Nan Jiang, Jiangtao Cao, Xibo Chen, Jiuren Zhou, Bing Chen, Genquan Han (Zhejiang University, China; Xidian University, China)
P1-45	0023: A 13-bit,1 MS/s Cyclic ADC, for high-speed CMOS Image sensor
	Qi Lv, Rensheng Shen, Yu Cheng, Guoqiang Zhong, Yang Qu, Yuchun (Dalian University of Technology, China)
P1-46	0110: An Area-Efficient 16-bit Four-channel R-2R DAC Based on Switching On-resistance Adaptive Calibration Technique
	Kejun Wu, Yuchen Liu, Yuhan Hu, Yu He, Zhen Yu, Ning Ning (University of Electronic Science and Technology of China, China)
P1-47	0215: A Background Calibration Method of Bandwidth Mismatch for Time-Interleaved ADCs Based on Neural Network
	Tianqi Yang, Longsheng Wang, Xin Zhao, Shubin Liu, Dengquan Li, Zhangming Zhu (Xidian University, China)
P1-48	0352: A Second-Order Dual-Charge-Pump Passive Noise Shaping SAR ADC for Medical Implant Devices
	Kangkang Sun, Xuanxin Ke, Haoning Sun, Yuchen Wang, Feng Yan, Jingjing Liu (Sun Yat-Sen University, China)
P1-49	0084: A 114.4-dB DR, 26-kHz BW Discrete-Time Incremental Zoom ADC
	Yuanhong Ding, Longjiang Jia, Jian Mei, Lei Deng, Rui Yin (Fudan University, China; National Integrated Circuit Innovation Center, China; Jiashan Fudan Institute, China)
P1-50	0087: A High-Resolution Low-Power Extended-Range Incremental ΣΔ ADC For Battery Management System
	Long Zhang, Quan Sun, Rui Liu, Zhe Zheng, Jingjing Zhang, Haitao Liu (Xi'an Aerosemi Technology Company Ltd., China; Beijing Smart-Chip Microelectronics Technology Company Ltd., China)
P1-51	0155: An Infrared AFE Chip and System with Non Invasive Blood Glucose Detection Output
	Bin Li, Jiyuan Guo, Chengzhen Xie, Jian Mei, Lei Deng, Rui Yin (Fudan University, China; National Integrated Circuit Innovation Center, China; Jiashan Fudan Institute, China)
	ALOS A 12 DVE OCCUS TIME INTERNAL DAYED NAME AND A 12 CONTROL
P1-52	O183: A 12-BIT 8GS/S TIME-INTERLEAVED PIPELINE-SAR ADC WITH CALIBRATION  Jie Pu, Jinda Yang, Jianwen Li, Rong Han, Xing Zhu, Lei Chen (Chengdu Sino Microelectronics Technology Co., Ltd., China)

P1-53	0238: An Ultra-High Frame Rate ROIC for Hyperspectral Detection
	Angyang Li, Ningning Li, Jian Mei, Lei Deng, Rui Yin (National Integrated Circuit
	Innovation Center, China; Jiashan Fudan Institute, China; Fudan University, China)
P1-54	0273: A Background Digital Calibration Method for DTCs Used in Digital PLL Employing Dual-Path DTC
	Renxuan Li, Xiaoyu Shan, Li Wang, Ang Hu, Dongsheng Liu (Huazhong University of
	Science and Technology, China)
P1-55	0310: A High-Precision Sigma-Delta ADC for Battery Management System
	Hao Xue, Liji Wu, Jing Hu, Zhiwei Li, Xiangmin Zhang (Heilongjiang University,
	China: Tsinghua University, China: Beijing National Research Center for Information
	Science and Technology, China)
P1-56	0413: Multi-Sampling Mode CDAC Design for a 12-bit 200MS/s Pipelined-SAR
11-30	ADC
	Tianyu Zhang, Fan Ye, Shunli Ma (Fudan University, China)
	0356: DSP-PUF: A Software PUF Based on Digital Signal Processor for IoT
P1-57	Security
	Tengfei Yuan, Pengjun Wang, Yuejun Zhang, Mingze Ren, Shuang Hu (Ningbo
	University, China; Wenzhou University, China)
	0042: 0042: A Q/V Band 49.6-54.5GHz,3.53dB NF,45dB Gain,2.09° Phase
P1-58	Error,2-Way Phased-Array Receiver for Satellite Application
	Congrui Li, Qi Zhao, Ruolan Chen, Shulan Chen, Yan Wang, Lei Zhang (Tsinghua
	University, China)
P1-59	0265: A Fractional-N SPLL Using Space-time Averaging and Phase Interpolator
	for Quantization Noise Reduction
	Shengxiang Liu, Ke Sun, Chengyu Yang, Dongsheng Liu, Ang Hu (University of Science and Technology, China)
	Science and Technology, China)
P1-60	0342: A 47 μW Wake-Up Receiver With -77dBm Sensitivity Using a Mixer-First Architecture
	Weitao He, Yaxin Zeng, Bin Jia, Hao Min, Hao Xu, Na Yan (Fudan University, China
	EPIC MEMS Corporation, China)
	21 TO 1121110 Corporation, Chilling
P1-61	0346: A Ka-Band CMOS Broadband Power Amplifier with 35.3% PAE for
	SATCOM Applications
	Zhiqing Liu, Yu Chu, Yuting Sun (Southwest China Institute of Electronic Technology China)
P1-62	0348: RF Front-End Chip Design for Ku-Band with 130nm CMOS Technology

	Huiquan Xie, Ziyu Wang, Tianrui Wang, Yifei Chen, Maliang Liu, Yintang Yang
	(Xidian University, China)
P1-63	0394: Back-gate Bias Assisting VCRO Design
	Chenglin Ye, Zheng Zhou, Xiaoyan Liu (Peking University, China)
P1-64	0034: A 3.2-to-7.1GHz Quad-Core Dual-Mode Oscillator Achieving 193.6 dBc/H Peak FoM
	Xiaoyu Shan, Renxuan Li, Mengming Zhang, Ang Hu, Dongsheng Liu (Huazhong University of Science and Technology, China)
P1-65	0301: A 20.6 to 30.5 GHz Two Stage Cascode LNA in 40nm CMOS for Phase Array Tranceiver
	Lei wang, Kefeng Han, Hao Xu, Rui Yin, Na Yan (Fudan University, China; Jiashan Fudan Institute, China)
P1-66	0338: A 12-32 GHz Power Amplifier with 32-dBm Psat and 25% PAE in 0.15 µ I GaN
	Xiangran Ni, Chunyue Bo, Tianyu Li, Qingyang Dong, Xin Jiang, Weijun Luo (University of Chinese Academy of Sciences, China; Institute of Microelectronics of Chinese Academy of Sciences, China)
P1-67	0427: A source-driven push-push doubler with wideband 2nd harmonic feedbac
	Yuyang Chen, Ao Zhang, Jianjun Gao, Jianjun Zhou (Shanghai Jiao Tong University China; Nantong University, China; East China Normal University, China)
P1-68	0367: Low Power Processor For IoT Device
	Jincheng Li, Jiyuan Bai, Zelin Wang, GengSheng Chen, Xiaofang Zhou (Fudan University, China; Jiashan Fudan Institute, China)
P1-69	0386: A Heterogeneous Integration System of Analog In Memory Computing an Field-Programmable Gate Array
	Hua Chen, Yiming Qu, Wenhao Wu, Yi Zhao (East China Normal University, China) China Nanhu Academy of Electronics and Information Technology, China; Zhejiang

## **Thursday**

#### Thursday, October 24, 9: 00 – 10: 30

Thursday, October 24, 9: 00 – 10: 30

Grand Ball Room

**Keynote Session K3** 

Sheraton Zhuhai Hotel 1st Floor

Session Chair: Prof. Francois Rivet, University of Bordeaux, France

K3-1	Integrated Circuit Innovation in the Age of AI
9: 00 ~ 9: 45	Prof. Boris Murmann, University of Hawaii, USA
K3-2	On-Chip ESD Protection: Methodologies, Challenges and Perspectives
9: 45 ~10: 30	Prof. Albert Wang, University of California, Riverside, USA
	Coffee Break

#### Thursday, October 24, 10: 30 – 12: 15

Thursday, October 24, 10: 45 – 12: 15

Grand Ball Room

**Panel Discussion** 

Sheraton Zhuhai Hotel 1st Floor

#### Opportunities and Challenges of Integrated Circuits in the AI Era

Tony Tae-Hyoung Kim (Nanyang Technological University, Singapore), Xiaoyao Liang (Shanghai Jiaotong University, China), Do Anh Tuan (A\*STAR, Singapore), Hao Yu (Southern University of Science and Technology, China), Chunmeng Dou (University of Chinese Academy of Sciences, China)

Session Chair: Prof. Jianguo Yang, Zhangjiang Laboratory, China

Dr. Hailan Yi, Zhangjiang Laboratory, China

#### Thursday, October 24, 13: 30 – 15: 15

Thursday, October 24, 13: 30 – 15: 15 Meeting Room 1

Session A1: AI Circuit Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Yan Li, Fudan University, China

	Title
A1-1	0468: Towards Efficient Computing Architecture and Chip For Embodied AI
	(invited)
13:30	
~14:00	Hongbin Sun (Xi'an Jiaotong University, China)
A1-2	0320: A High-Performance Multicore Testing Platform for Multi-Scenario
	Applications
14:00 ~14:15	Zipeng Ling, Tianshu Zhuo, Zhuoyuan Yang, Jinhong Ye, JunHan, Jingtao Zhang (State Key Laboratory of Integrated Chips and Systems, China; ZTE Corporation,
	China)
A1-3	0317: S-SIFT: A Simple SIFT Algorithm with High Efficiency
	Yixue Wang, Yujie Huang, Liyuan Peng, Mingyu Wang, Wenhong Li, Minge Jing,
14:15 ~14:30	Xiaoyang Zeng (Fudan University, China; Shanghai ExploreX Technology Co., Ltd.,
11.50	China)
	0345: Design of a High-Speed SAR Processor Based on the Chirp Scaling
A1-4	Algorithm
14:30	Xianghe Cui, Yukun Song, Yurun Zhang, Jingyi Hu, Zhenmin Li, Duoli Zhang (Hefei
~14:45	University of Technology, China)
A1-5	0196: Accelerating Matrix-Vector Multiplications of Large Language Models via
	Efficient Encoding
14:45	Yongjin Tao, Wendi Sun, Song Chen, Yi Kang (University of Science and Technology
~15:00	of China, China)
~13.00	of China, China)
11.6	0397: Flexible yet Efficient Transformer Acceleration with Unified Sparse Attention Support on FPGA
A1-6	
15:00	Linfeng Zhong, Qingyu Guo, Runsheng Wang, Yuan Wang, Meng Li (Peking

Thursday, October 24, 13: 30 – 15: 15

Session B3: Analog Circuit III

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Yubin Zhao, Sun Yat-sen University, China

	Title
B3-1	0296: Beyond Bandwidth Trade-off: Simultaneous Wireless Power and

	Data Transfer System Design for Biomedical Implants (Invited)
13:30	Quanrong Zhuang, Junyi Sun, Xusheng Zhang, Bo Li, Yi Shi, Hao Qiu (Nanjing
~14:00	University, China)
B3-2	0011: A High Precision Operational Amplifier with Improved Bias Current Cancellation Circuit
14:00	Zhili Zhang, Siyuan Yao, Hailong Wei (Xi'an Microelectronics Technology Research
~14:15	Institute, China)
B3-3	0030: A 0.11-pJ/bit True Random Number Generator Based on a Clocked Current-Starved Inverter
14:15 ~14:30	Kai Cheng, Chaowei Yang, Rui P. Martins, Pui-In Mak, Yong Chen (University of Macau, Macao, China; Universidade de Lisboa, Portugal; Tsinghua University, China)
B3-4	0256: A Super-Mixed Current Decay Mode for Reducing the Angular Position  Error in Stepper Motor
14:30 ~14:45	Jian Fang, XuruiChen, Huajie Liu, Yuhan Jin (University of Electronic Science and Technology of China, China)
~14:43	Technology of China, China)
B3-5	0065: A 109 dB 44-pArms Current Readout Circuit with Automatic Current Control for Multimodality Electrochemical Sensing
14:45 ~15:00	Lina Wang, Jianzheng Li, Weiming Hu, Yajie Qin (Fudan University, China)
B3-6	0080: A Low Temperature Coefficient Bandgap Reference For Temperature Sensor System
15:00 ~15:15	Longjiang Jia, Yuanhong Ding, Jian Mei, Lei Deng, Rui Yin (Fudan University, China; National Integrated Circuit Innovation Center, China; Jiashan Fudan Institute, China)

Thursday, October 24, 13: 30 – 15: 15

Session C3: RF Circuit I

Session Chair: Prof. Gengzhen Qi, Sun Yat-sen University, China

Meeting Room 3

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

$\begin{bmatrix} & & & & & & & & & & & & & & & & & & &$	75: High-Efficiency Power Amplifier Design for Bluetooth Low Energy
C3-1 Ap	oplications (invited)
13:30   Ma ~14:00   Li, Un	naratha Kumar Thangarasu, Li Shuai, Yu Hongshi, Ge Wansi, Liu Yuqing, Nagarajan ahalingam, Meng Fanyi, Kaixue Ma, Juin J. Liou, Bo Wang, Younan Hua, Xiaomin, Lu Zhenghao, and Kiat Seng Yeo (Tianjin University, China; North Minzumiversity, China; Singapore University of Technology and Design, Singapore; intech Nano-Technology Services Pte Ltd, Singapore; Soochow University, China)

C3-2	0104: A 0.15-6.5GHz Stacked CMOS Power Amplifier With Low-Frequency
	Bandwidth Extension
14:00	Chilian Dang Wai Li Vingga Ma Fan Chan Hangton Va (Fudan Haingwith China)
~14:15	Shijiao Dong, Wei Li, Xingyu Ma, Fan Chen, Hongtao Xu (Fudan University, China)
C2 2	0269: A 2-to-2.7GHz Class-G Switched-Capacitor PA with Cascode
C3-3	Switch-Reused Structure Achieving 25.92dBm Peak Power and 42% Efficiency
14:15	L'a Dans Canadan Oi (Can Vet and Hairmaite China)
~14:30	Jie Deng, Gengzhen Qi (Sun Yat-sen University, China)
C3-4	0294: A X-band High Linearity Tunable Bandpass Filter in 130nm CMOS
14:30	Tianrui Wang, Ziyu Wang, Huiquan Xie, Yifei Chen, Haokun Lan, Maliang Liu,
~14:45	Yintang Yang (Xidian University, China)
C2.5	0302: Analysis of Polar and Quadrature Digital Transmitters for Wi-Fi7
C3-5	Applications
14:45	Limes Co. Ven Vin (Feedon Heimanite China)
~15:00	Lixuan Cao, Yun Yin (Fudan University, China)

Thursday, October 24, 13: 30 – 15: 15

Session D3: Novel Device III

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Mansun Chan, The Hong Kong University of Science and Technology, China

	Title
D3-1	0458:Low-Dimensional Materials Enabled Wearable Circuits With Multi-level
	Detection and Wireless Communication Modules (invited)
13:30	Li Tao (Southeast University, China)
~14:00	Li Tao (Southeust University, China)
D3-2	0461: Memristive Circuits Based on Two-dimensional Layered Hexagonal Boron Nitride for Radiofrequency Applications (invited)
14:00 ~14:30	Sebastian Pazos (King Abdullah University of Science and Technology, Saudi Arabia)
D3-3	0452: Two-dimensional Ferroelectricity: Polarization Modulation and New Device (Invited)
14:30 ~15:00	Fucai Liu (University of Electronic Science and Technology of China, China)
D3-4	0475: Impact of Gate Overlap Length Modulation on Electrical Characteristics and Subthreshold Swing in Nanosheet TFETs with Varying Tunneling Mechanisms
15:00	Zheng-Hong Zhong, Wei-Heng Tai, Jyi-Tsong Lin (Sun Yat-Sen University, Taiwan,

~15:15	China)

Thursday, October 24, 13: 30 – 15: 15

Session E3: Power Device III

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Bo Zhang, University of Electronic Science and Technology of China (UESTC), China

	Title
E3-1	0255: The Status of WBG Devices Towards Net-Zero Solutions (invited)
13:30	Milroel Östling (VTH Bough Institute of Technology Sweden)
~14:00	Mikael Östling (KTH Royal Institute of Technology, Sweden)
E3-2	0121: Impact of the Resistive Silicon Base Wafer on Substrate Coupling in Power
20 2	Integrated Circuits in GaN-on-Si Technology
14:00	Zijin Jiang, Rui (Ray) Yao, Miao Cui, Zhao Wang, Sang Lam, Stephen Taylor
~14:15	(Xi'an Jiaotong-Liverpool University, China; The University of Liverpool, UK)
E3-3	0128: A Novel Snapback-free Double-RESURF Reverse conducting LIGBT with
E3-3	<b>Dual Conduction Paths</b>
	Yun Xia, Yuxi Wan, Wei Zeng, Yu Shi, Xiaoping Wang, Wei Liu, Haizhao Zhi,
14:15	Ziwei Zhou, Xixi Luo, Ruize Sun, Xiaoming Wang, Yan Wang, Wanjun Chen
~14:30	(Shenzhen Pinghu Laboratory, China; University of Electronic Science and
	Technology of China, China; Tsinghua University, China)
	0168: Comparsion of SiC Planar and Trench Junction Barrier Schottky Diode
E3-4	With Surge Current Capability
14:30	Ziming Zhao, Yancong Liu, Hao Yuan, Fengyu Du, Yu Zhou, Keyu Liu, Xiaoyan
~14:45	Tang, Qinwen Song, Yuming Zhang (Xidian University, China)

Thursday, October 24, 13: 30 – 15: 15

Session F3: Memory Device III

Floor
Session Chair: Prof. Anquan Jiang, Fudan University, China

Meeting Room 6

Sheraton Zhuhai Hotel 2<sup>nd</sup>

	Title
F3-1	0266: Simulation of Program/Erase Cycling and Retention Loss in 3-D CTF
	NAND Flash (invited)
13:30	Anuj Kumar, Ravi Tiwari, Souvik Mahapatra (Indian Institute of Technology Bombay,
~14:00	India)
F3-2	0275: Switch-off Mechanisms in GeAsTe Ovonic Threshold Switching Selector
	Device (invited)
14:00	Zeyu Hu, Zheng Chai, Weidong Zhang, Jianfu Zhang (Liverpool John Moores

~14:30	University, UK; Xi'an Jiaotong University, China)
E2 2	0334: Orthorhombic-I (Pbca) Phase: Origin of Antiferroelectricity in HfZrO
F3-3	Films (invited)
14:30	Wei Liu, Zeping Weng, Jianguo Li, Wenchao Yan, Yiming Qu, Yi Zhao (Zhejiang
~15:00	University, China; East China Normal University, China)
F2 4	0254: The Maximum Storage Capacity of Open-loop Written RRAM is Around 4
F3-4	Bits
15:00	Vanaviana I.; Chiaina Wana 7hana Sun (Bahina Hainawita China)
~15:15	Yongxiang Li, Shiqing Wang, Zhong Sun (Peking University, China)

## Thursday, October 24, 15: 30 – 17: 15

Thursday, October 24, 15: 30 – 17: 15 Meeting Room 1

Session A2: Security Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Yan Li, Fudan University, China

	Title
A2-1	0469: Hardware Security Linking Everything: from Lightweight PUF to
	Post-Quantum Cryptography Hardware (invited)
15:30	Yijun Cui, Jiang Li, Jiansheng Chen, Fei Lyu, Chenghua Wang, Weiqiang Liu
~16:00	(Nanjing University of Aeronautics and Astronautics, China)
A2-2	0219: Backward-edge Control Flow Integrity based on Return Address
A2-2	Encryption
16:00	Fengshuo Tian, Kaixuan Wang, Jun Han (Fudan University, China)
~16:15	Tengshuo Han, Kaixuan wang, Jun Han (Puaan University, China)
A2-3	0239: Stability Enhancement Technique for Monostable PUF Based on Hysteresis Effect of Schmitt Trigger
16:15	Ruize Xu, Gang Li, Pengjun Wang, Hui Li, Xudong Wu (Wenzhou University, China)
~16:30	Kuize Au, Gang Li, Tengjun wang, Hui Li, Audong wu (wenzhoù Oniversity, China)
A2-4	0355: A Reliable Current Starved Inverter PUF Based on SRAM Memory Structure
16:30	Mingze Ren, Pengjun Wang, Yuejun Zhang, Shutong Zhang, Zhikang Chen, Tengfei
~16:45	Yuan (Ningbo University, China; Wenzhou University, China)
A2-5	0354: An Efficient Convolutional Neural Network Hardware IP for Epilepsy
A2-3	Detection
16:45	Yi Gong, Yuejun Zhang, Jiangtao Tu, Rongxin Zou, Liang Wen (Ningbo University,
~17:00	China)

A2-6	0082: TLBshield: A Low-cost Secure Reinforce on Translation Lookaside Buffer
	to Mitigate the Speculative Attacks
17:00	Yuyang Liu, Runye Ding, Yujie Chen, Pujin Xie, Yao Liu, Zhiyi Yu (Sun Yat-sen
~17:15	University, China)

Thursday, October 24, 15: 30 – 17: 15

Session B4: Mixed Signal I

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Yubin Zhao, Sun Yat-sen University, China

	Title
B4-1	0038: Toward Unification of Digital Error Correction Algorithms for ADCs with
	Redundancy (invited)
15:30	Haruo Kobayashi, Tomohiko Ogawa, Yutaro Kobayashi, Kentaroh Katoh, Jiangling
~16:00	Wei (Gunma University, Japan; Fukuoka University, Japan; Yibin University, China)
B4-2	A1.2-V 2-GS/s Trimming-Free Input Buffer with Robust Output Common-mode Voltage (invited)
16:00 ~16:30	Wei Zhang, Xizhu Peng, He Tang (UESTC, China)
B4-3	0260: A 12-bit 1-MS/s SAR ADC Using $V_{cm}$ -based Split MSB Switching and Segmented CDAC
16:30	Zheng-Han Chen, Ya-Cong Zhang, Wen-Gao Lu, Zhong-Jian Chen (Peking
~16:45	University, China)
B4-4	0333: A Simplified and Accelerated Opportunistic Bit Weight Calibration for High-Resolution ADCs
16:45 ~17:00	Bingbing Ma, Wei Li, Hongtao Xu (Fudan University, China)
B4-5	0154: Background Calibration for Bit Weights in Pipelined SAR ADCs Using Split ADC Architecture
17:00	Zecheng Zhou, Longsheng Wang, Dongxian Ye, Yexin Zhu, Dengquan Li, Zhangming
~17:15	Zhu (Xidian University, China)

Thursday, October 24, 15: 30 – 17: 15

Session C4: Sensor and MEMS I

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Luda Wang, Peking University, China

Prof. Fan Ye, Fudan University, China

Title
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C4-1	0108: Atomically Thin Graphene Nanopore based MEMS Iontronic Devices for
	Sensing, Separation and Energy Applications (invited)
15:30	Lyda Wang Dyiyang Cang Ninggan Way (Daking Haiyangita China)
~16:00	Luda Wang, Ruiyang Song, Ningran Wu (Peking University, China)
C4-2	0132: Smart Vision Chip (invited)
16:00	Livron Liv (Institute Of Comican dustons Chinese Academy Of Sciences Chine)
~16:30	Liyuan Liu (Institute Of Semiconductors, Chinese Academy Of Sciences, China)
C4.2	0191: Systems-on-Chips for Invasive Brain-Computer Interfaces: Challenges and
C4-3	Opportunities (invited)
16:30	Lie Vone Mahamad Sayyan (Wastlaha Lluis augita, China)
~17:00	Jie Yang, Mohamad Sawan(Westlake University, China)
C4.4	0410: Multi-physics Simulation and Application of Ion Gel Based Triboelectric
C4-4	Nanogenerators
17:00	Chen Liu, Ruibo Wang, Ruiyi Gao, Yuming Zhang (Xidian University, China; Air
~17:15	Force Engineering University, China)

Thursday, October 24, 15: 30 – 17: 15

Session D4: Novel Device IV

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Zhigang Ji, Shanghai Jiaotong University, China

	Title
D4-1	0264: Recent Progress in the Development of Complementary Field-Effect Transistors (invited)
15:30	Mansun Chan, Shengdong Zhang (The Hong Kong University of Science and
~15:57	Technology, Hong Kong, China; Peking University, China)
D4-2	0471: SC-CMOS: Revolutionizing Semiconductor Technology with High Electron Mobility Materials and Advanced Node Optimization (invited)
15:57	Jyi-Tsong Lin (Sun Yat-Sen University, Taiwan, China)
~16:24	
D4-3	0074: Metal-Oxide Thin-Film Transistors for Artificial Neural Networks (invited)
16:24	Yushen Hu, Tengteng Lei and Man Wong (The Hong Kong University of Science and
~16:51	Technology, Hong Kong, China)
D4-4	0203: Cryogenic Threshold Voltage and On-current Variability Analysis of GAA
ד-דע	Nanosheet FETs at 4K
	Zihao Liu, Tomoko Mizutani, Kiyoshi Takeuchi, Takuya Saraya, Hiroshi Oka,
16:51	Takahiro Mori, Masaharu Kobayashi1, Toshiro Hiramoto (The University of Tokyo,
~17:03	Japan; National Institute of Advanced Industrial Science and Technology (AIST),
	Japan)

D4-5	0188: Reverse-Biased PN Junction Isolation for Leakage Suppression and Strain
	Enhancement in Gate-All Around Nanosheet FETs
	Boqian Shen, Chunlei Wu, Yumin Xu, Fei Zhao, Hanzhi Gu, Jian Ma, Yueyuan Yu,
17:03	Yiming Xia, Qingqing Sun, David Wei Zhang (Fudan University, China; Shanghai
~17:15	Integrated Manufacturing Innovation Center Co., Ltd, China; Jiashan Fudan Institute,
	China)

Thursday, October 24, 15: 30-17: 15 Meeting Room 5 **Session E4: Power Device IV** Sheraton Zhuhai Hotel  $2^{nd}$  Floor **Session Chair:** Prof. Bo Zhang, University of Electronic Science and Technology of China (UESTC), China

	Title
E4 1	0405: Comparative Study on Reliability of Conventional SiC MOSFET and JBS
E4-1	Integrated SiC MOSFET (invited)
15:30	Moufu Kong, Shurui Li, Hongfei Deng, Bo Yi, Hongqiang Yang, Sen Gong
~16:00	(University of Electronic Science and Technology of China, China)
E4-2	0445: Study on Single Event Effect of SiC MOSFET by Proton Irradiation
16.00	Wende Huang, Chengwen Fu, Yao Ma, Mingmin Huang, Xiaoping Dong, Qiang Yu
16:00	(Sichuan University, China; Sichuan Suining Lippxin Microelectronics Co., Ltd,
~16:15	China)
E4-3	0341: Investigating Single-Event Burnout in 4H-SiC Inverters: Experiments and
E4-3	Simulations
16.15	Yong Gu, Yurui Yang, Hongyang Wen, Xiangyu Hou, Runhua Huang, Ao Liu, Bai
16:15	Song, Jie Ma, Siayang Liu, Long Zhang, Weifeng Sun (Southeast University, Nanjing
~16:30	China; Nanjing Electronic Device Institute, China)

Thursday, October 24, 15: 30-17: 15 Meeting Room 6 **Session F4: Memory Device IV** Sheraton Zhuhai Hotel  $2^{nd}$  Floor **Session Chair:** Prof. Anquan Jiang, Fudan University, China

	Title
F4-1	DRAM Trend and Challenges
15:30	Robert Liu (CXMT Corporation, China)
~16:00	
F4-2	0335: Phase-Change Materials and Their Applications (invited)
16:00	Van Via (Comma Hairanaita, Iranga)
~16:25	You Yin (Gunma University, Japan)

F4-3	0449: High-Density and High-Reliability RRAM for Memory and Computing
	Applications (invited)
16:25	Yimao Cai, Xiahong Zhou, Zongwei Wang, Lin Bao, Ling Liang, Cuimei Wang, Ru
~16:50	Huang (Peking University, China)
F4-4	0343: Impact of Different MAC Schemes on Computing In Memory based on
Г4-4	1T1R Array
16:50	Ruiqing Xie, Gaoqi Yang, Zongwei Wang, Linbo Shan, Jinshan Li, Chaoyi Ban, Lin
~17:03	Bao, Ling Liang, Cuimei Wang, Yimao Cai, Ru Huang (Peking University, China)
F4-4	0426: Investigation of Gate Injection Charges Behavior on FeFETs with
Г4-4	TiN/Al <sub>2</sub> O <sub>3</sub> /Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> /SiON/Si Structure by Analyzing ISPP/ISPE
	Jia Yang, Runhao Han, Saifei Dai, Tao Hu, Xianzhou Shao, Kanyi Li, Wenbo Fan,
	Xiaoqing Sun, Junshuai Chai, Hao Xu, Kai Han, Xiaolei Wang, Wenwu Wang,
17:03	Tianchun Ye (Key Laboratory of Fabrication Technologies for Integrated Circuits,
~17:15	Chinese Academy of Sciences, China; Institute of Microelectronics, Chinese Academy of
	Sciences, China; University of Chinese Academy of Sciences, China; Weifang
	University, China)

## Thursday, October 24, 17: 30 - 18: 30

Thursday, October 24, 17: 30 – 18: 30

**Poster Session II** 

Sheraton Zhuhai Hotel 1st Floor

	Title
D2 1	0071: Assembly of Oxidized/Intrinsic 2D MXene Film for Improved Absorption
P2-1	Electromagnetic Shielding
	Yulin Guo, Siteng Li, Jiafeng Song, Yilin Sun, Zhifang Liu, Weijia Luo (Beijing
	Institute of Technology, China; Tsinghua University, China)
P2-2	0149: Semimetal Alloy Contact with Low Resistivity and Enhanced Thermal
1 2-2	Budget for MoS <sub>2</sub> FETs
	Kwok-Ho WONG, Mansun CHAN (The Hong Kong University of Science and
	Technology, Hong Kong, China)
P2-3	0243: Copper Ion Migration in van der Waals CuInP <sub>2</sub> S <sub>6</sub> Devices with Vertical
	and Lateral Structures
	Jie Li, Yirong Guo, Pengying Chang (Beijing University of Technology, China)
P2-4	0382: Edge-Dependent of Threshold Voltage in MoS <sub>2</sub> Nanoribbon-Based 2D FETs
	Zhirong Peng, Mansun Chan (The Hong Kong University of Science and Technology,
	Hong Kong, China)
P2-5	0438: Effect of Layer Thickness on the Transport Properties of ALD-deposited

	ZnO/In <sub>2</sub> O <sub>3</sub> Heterojunction Thin-film Transistors
	Zhenwei Li, Tiaoyang Li (Fuzhou University, China)
P2-6	0417: Foundamentals of Low-Resistive Indium-Violet Phosphorene Top Contact:
1 2-0	an ab-initio NEGF Study
	Huaipeng Wang, Sicheng Liu, Shuaihong Li, Zhifang Liu, Yilin Sun, Jianlong Xu,
	Dan Xie (Tsinghua University, China; Beijing Institute of Technology, China;
	Soochow University, China)
	0095: Broadband Photodetectors Based on Graphene/Perovskite Hybrid
P2-7	Structure with Ferroelectric Gating
	Zhongyang Liu, Shuangqi Dong, Mingjie Li, Huaipeng Wang, Dan Xie, Yilin Sun
	(Beijing Institute of Technology, China; Tsinghua University, China)
	(Beging Institute of Technology, China, Isinghia Chiversity, China)
P2-8	0363: Interconnection Design of Chiplet Technology
1 2-0	Ning Chen, Chang Wu (Fudan University, China)
	Ning Chen, Chang wu (Fudun University, China)
	0103 Fff 4 LM LL G4 L FDCOLMOSEET 4 C
P2-9	0102: Effects and Modeling Study on FDSOI MOSFETs at Cryogenic
	Temperature
	Zhipeng Ren, Yibo Hu, Yizhe Yin, Ruiyong Zhao, Jing Chen (Shanghai Institute of
	Microsystem and Information Technology, China)
P2-10	0247: Improved Channel Width and Morphology of Epi Silicon FinFET via Low
	Thermal Budgets Fin Thinning Technology
	Peng Wang, Yupeng Lu, Guanqiao Sang, Renjie Jiang, Lei Cao, QingKun Li, Lianlian
	Li, hang zhang, zhonrui wang, meihe zhang, Qingzhu Zhang, Junfeng Li; Huaxiang
	Yin (Institute of Microelectronics, China; University of Chinese Academy of Sciences
	China)
P2-11	0364: Deep Investigation into Variability of Complementary Dopant Segregated
F 2-11	Tunneling FET Based on Foundry Platform
	Rundong Jia, Jianfeng Hang, Kaifeng Wang, Yongqin Wu, Hongyan Han2, Ye Ren,
	Weihai Bu, Runsheng Wang, Qianqian Huang, Ru Huang (Peking University, China;
	Seimiconductor Technology Innovation Center (Beijing), China)
	0379: Investigation of Common-Gate and Split-Gate Structures Based on CFET
P2-12	Standard Cells
	Peishun Tang, Rongzheng Ding, Xiaona Zhu, Shaofeng Yu (Fudan University, China,
	6, 6 6,
	0187: Exploration of the effect of silver impurity on the minority carrier lifetime
P2-13	of semiconductor
	Xin Tian, Peizhi Zhao, Yudong Li, Jun Xu, Tianling Ren (Tsinghua University, China
	Jiangsu Xinhua Semiconductor Technology Co., Ltd.; China)
D2 14	02/7, E-bai-ston and El-stail 1/01
P2-14	0267: Fabrication and Electrical Characterization of Mo/Hf <sub>x</sub> Zr <sub>1-x</sub> O <sub>2</sub> /Mo

	ferroelectric capacitors
	Chunsheng Jiang, Wencai Du, Qin Xie (Guangxi Normal University; China)
	gg,g,
P2-15	0116: Effect of Cascade Current Density and Plating Time on TSV Filling Effect in DC Power Supply
	Weifeng Chen, Lijuan Peng, Xiaohui Wang, Fangzhou Wang, Guojian Ding, Qi Feng,
	Ping Yu, Peng Zuo, Feng Liu, Jiang Ma, Yang Wang, Haiqiang Jia, Hong Chen
	(Songshan Lake Materials Laboratory, China; Shenzhen University, China)
P2-16	0396: High-Performance Carbon Nanotube Optoelectronic Transistors for Memory Applications
	Shuang Liu, Heyi Huang, Yanqing Li, Yadong Zhang, Feixiong Wang, Yupeng Lu,
	Renjie Jiang, Jiali Huo, Huaxiang Yin (Institute of Microelectronics, China; University
	of Chinese Academy of Sciences, China)
P2-17	0414: Investigation of the channel width dependence of IGZO TFT by
	experiment and TCAD simulation
	Yanyu Yang, Yupeng Lu, Shuang Liu, Renjie Jiang, Jie Luo, Yunjiao Bao, Peng Wang,
	Gaobo Xu, Huaxiang Yin (Institute of Microelectronics, China; University of Chinese
	Academy of Sciences, China)
P2-18	0120: A Test and Evaluation Platform for Quantitative Analysis of High-Reliability Designs
	Yifeng Huang, Wenqing Wan, Chang Wu (Fudan University, China)
P2-19	0171: Hot-Carrier Injection Characterization of n-LDMOS Transistors and Stress Tests in a Buck Converter Configuration
	Chun Yee Chu, Wai Tung Ng (University of Toronto, Canada)
P2-20	0044: Automated Verification of Functional Interface Connections in Circuit Schematics
	Keli Long, Xingyu Gao, Lei Li, Jinxiang Wang, Fangfa Fu, Liangquan Qiao, Jinghan
	Zhou (Harbin Institute of Technology, China; 58th Research Institute of China
	Electronics Technology Group Corporation, China)
D2 22	0214: Co-Optimization Design Method of Temperature Variation and Circuit
P2-22	Aging in Digital Circuits
	Songxuan He, Wangyong Chen, Ling Xiong, Linlin Cai (Sun Yat-sen University,
	China)
P2-23	0308: Boolean Matrix Factorization Algorithm based on Error Shaping
	Technique and its Application on Approximate Logic Synthesis
	Botao Xiong, Runhua Yang, Yuchun Chang (Dalian University of Technology, China)
P2-24	0148: Automatically Device Sizing of Analog Circuit through Sequential
1 2-47	or io. Materialization Device Sizing of Analog Circuit through Sequential

	Model-Based Optimization with Circuit Recognition
	Shun-Qi DAI, Xiao WANG, Yuan LEI, Bei-Ping YAN (Hong Kong Applied Science
	and Technology Research Institute (ASTRI), Hong Kong, China)
P2-25	0229: Vanadium Oxide-Based Artificial Synapses for Construction of Artificial Neural System
	Zhuoling Zhou, Libin Liang, Hongzhi Chen, Changjiu Teng, Shilong Zhao, Wenjun
	Chen (Foshan University, China)
P2-26	0048: High performance FeFET with α-IGZO Channel Enabled by
	Atomic-Layer-Deposited HfO <sub>2</sub> Interfacial Layer
	Yinchi Liu, Hao Zhang, Xinlong Zhou, Dmitriy Anatolyevich Golosov,
	Chenjie Gu, Hongliang Lu, Shijin Ding, and Wenjun Liu (Fudan University, China;
	Research Institute of Fudan University in Ningbo, China; Belarusian State University
	of Informatics and Radioelectronics, Republic of Belarus; Ningbo University, China;
	Zhangjiang Fudan International Innovation Center, China)
	0097: A Simulation Study on Cell Scaling Impacts in 3D Charge-trapping (CT)
P2-27	Flash Memory
	Wanyu Li, Haitao Dong, Qianwen Wang, Yang Feng, Xuepeng Zhan, Jixuan Wu,
	Jiezhi Chen (Shandong University, China; Qingdao University of Science &
	Technology, China)
P2-28	0390: Comprehensive Charaterizations on Read Disturbs in QLC Charge-Trap (CT) 3D NAND Flash
	Shaoqi Yang, Xiaohuan Zhao, Peng Guo, Qianwen Wang, Guangkuo Yang1, Xinyi
	Guo, Pengpeng Sang, Jixuan Wu, Xuepeng Zhan, Jiezhi Chen (Shandong University,
	China; Shandong Sinochip Semiconductors Co., Ltd, China; Qingdao University of
	Science & Technology, China)
	0047: Aspect Ratio Dependent Optimization and Comparison of Specific
P2-29	ON-Resistance of SJ and Hk MOSFETs with Extremely High Permittivity
	Chenxing Wang, Zhentao Xiao, Zonghao Zhang, Zhenghao Jin, Zhiwan Liu, Zonglin
	Li, Zhemin An, Yunteng Jiang, Ruguan Li, Haimeng Huang, Hongqiang Yang
	(University of Electronic Science and Technology of China, China; GRG Metrology &
	Test Group Co., Ltd., China)
D2 20	0092: Simulation Study of the Impact of Split Gate on SiC DTMOS Short Circuit
P2-30	Withstand Capability
	Zixun Chen, Jinping Zhang, Yang Liu, Xudong Ma, Bo Zhang (University of
	Electronic Science and Technology of China, China; Weihai Singa Electronics
	CO.LTD, China)
P2-31	0143: Improved Hall Mobility Measurement Distinguishing Interface Capturing
	Effect in 4H-SiC Inversion Channel

	T
	Xiangrui Fan, Hao Fu, Xinyu Zhang, Zilong Wu, Jiameng Sun, Jiaxing Wei, Siyang
	Liu, Weifeng Sun (Southeast University, China)
P2-32	0163: A Superior SiC Lateral MOSFET with Patterned P-bury Layer Made on N-type Wafers
	Xuke Yan, Junji Cheng, Xiaojun Fu, Bo Yi, Haimeng Huang, Hongqiang Yang
	(University of Electronic Science and Technology of China, China; The 24th Research
	Institute of China Electronics Technology Group Corporation, China)
P2-33	0272: High Performance Termination Design and Fabrication For SiC MOSFET Device
	Lei Huang, Junhou Cao, Chenlu Wang, Hao Fu, Jiaxing Wei, Siyang Liu, Weifeng Su
	(Southeast University, China)
	0422: Analysis of The Separation Degree For P-pillar in SiC Super-Junction
P2-34	Structure Through "Multiple Epitaxy-Ion Implantation" Route
	Hao-Bo Kang, Hao Yuan, Feng-Yu Du, Yu Zhou, ke-Yu Liu, Xiao-Yan Tang, Chao
	Han, Qing-Wen Song, Yu-Ming Zhang (Xidian University, China; The Xidian-Wuhu
	Research Institute, China)
	nescuren institute, China)
	0433: Numerical Analysis of the CIBL Effect on ShortCircuit Characteristics of
P2-35	DG-CSTBTs with Reduced Mesa Width
	Zhengyu Lang, Jinping Zhang, Shiwei Zheng, Shuyang Huang, Haonan Deng, and B
	Zhang (University of Electronic Science and Technology of China, China; Nanjing
	SilverMicro Electronics, China)
P2-36	0441: Innovations in GaN HEMT Design: Achieving Superior Power Output and Thermal Management
	Shiming Li, Bowen Yang, Mei Wu, Ling Yang, Bin Hou, Meng Zhang, Xiaohua
	Ma, Yue Hao (Xidian University, China)
P2-37	0446: An Enhanced RC-IGBT Incorporating Superjunction and Discontinuous Field Stop Layers for Improved Efficiency
	Yiming Jia, Jieyu Long, Zhiwei Jing, Haimeng Huang, Hongqiang Yang (University
	Electronic Science and Technology of China, China)
	0105: Simulation Study on 1200V CS-SemiSJ-IGBT for Reduced Switching Loss
P2-38	and Fast Switching
	Luping Li, Zehong Li, Peng Chen, Yuzhou Wu, Qiansheng Rao, Ming Li, Haifeng
	Qin, Li Wan, Yang Yang, Wei Li, Min Ren (University of Electronic Science and
	Technology of China (UESTC), China; China Resources Microelectronics
	(Chongqing) Ltd., China; Shanghai Super Semiconductor Technology Company Ltd.,
	China)
P2-39	0104. A Dual Cata Triggar Thymistan for Dadusing the Brokekility of F-1-
1 4-37	0194: A Dual-Gate Trigger Thyristor for Reducing the Probability of False

	Triggering
	Pengcheng Xing, Qingbo Wan, Jie Huang, Ruize Sun, Chao Liu, Wanjun Chen
	(University of Electronic Science and Technology of China (UESTC), China)
P2-40	0202: ultra fast diode avalanche shaper with floating junction
	Zhen Yang, Yu Zhou, Xiao-Yan Tang, Chao Han, Qing-Wen Song, Yu-Ming Zhang
	(Xidian University, China; Xidian-Wuhu Research Institute, China)
D2 41	0204: Silicon Carbide Diode Avalanche Shaper with Multi-Point Quasi-Uniform
P2-41	Triggering
	Lin Cheng, Yu Zhou, Xiao-Yan Tang, Chao Han, Yu-Ming Zhang, Qing-Wen Song
	(Xidian University China; Xidian-Wuhu Research Institute, China)
D2 42	0209: Super Field Plate LIGBT with Improved Performance for Both Cell and
P2-42	Terminal Region
	Weihao Lu, Jing Li, Jitong Wang, Chaoyang Peng, Chunwei Zhang (University of
	Jinan, China)
P2-43	0248: High-temperature oxidation of 4H-SiC and gate oxide reliability
P2-43	dependence on oxidation temperature
	Baoyan Feng, Xiaoyan Tang, Yi bo Zhang, Chao Han, Hao Yuan, Qing wen Song
	(Xidian University, China; Xidian-Wuhu Research Institute, China)
P2-44	0299: Optimization for a High-voltage Recessed-gate β- Ga <sub>2</sub> O <sub>3</sub> MOSFET by Gate
1 2-44	and Drain Field Plate Technology
	Bo Yi, Yuan Qiao, Ming Dai, Fan Xu, JunJi Cheng, HaiMeng Huang, MouFu Kong,
	XingLi Jiang, HongQiang Yang (University of Electronic Science and Technology of
	China, China; Chongqing Institute of Microelectronics Industry Technology, China;
	Chengdu Semi-Future Technology Co., Ltd, China)
P2-45	0315: A Novel Voltage Sensor with Composite Trench Structure for High
	Voltage IGBT
	Yang Yang, Ze-Hong Li, Senior Member, IEEE, Li-Hang Dong, Wei Li, Peng-Fei Jia,
	Zhi-Yu Yang, Li Wan, Yi-Shang Zhao, Tong-Yang Wang, Zi-Ming Xia (University of
	Electronic Science and Technology of China, China; China Resources
	Microelectronics (Chongqing) Limited, China; Chongqing Institute of
	Microelectronics Industry Technology, China)
D2 ::	
P2-46	0316: A Novel Triggered Voltage Sensing Structure for High Voltage IGBT
	Yang Yang, Ze-Hong Li, Senior Member, IEEE, Li-Hang Dong, Wei Li, Peng-Fei Jia,
	Zhi-Yu Yang, Li Wan, Yi-Shang Zhao, Lu-Ping Li, Zi-Ming Xia, and Tong-Yang Wang
	(China Resources Microelectronics (Chongqing) Limited, China; University of
	Electronic Science and Technology of China, China; Chongqing Institute of
	Microelectronics Industry Technology, China)

P2-47	0374: Investigation of Threshold Voltage Instability in p-GaN Gate HEMTs under Surge Current Stress
	Xiaoming Wang, Yu Shi, Chunhua Zhou, Haizhao Zhi, Yun Xia, Ruize Sun, Xinghuan Chen, Wanjun Chen, Bo Zhang (University of Electronic Science and Technology of
	China, China; Shenzhen Pinghu Laboratory, China; China Electronic Product Reliability and Environmental Testing Research Institute, China)
P2-48	0408: A Novel Ga <sub>2</sub> O <sub>3</sub> High-k Trench MOSFET with Improved Forward and Reverse Performance
	Moufu Kong, Lewei Lyu, Haoran Wang, Zhaoyu Ai, Xinyang Chen, Fanxin Meng, Qiang Hu (University of Electronic Science and Technology of China, China; Chengdu High-tech Development Co.Ltd, China; Chengdu Semi-Future Technology Co. Ltd, China)
P2-49	0054: A Nonlinear Behavioral Modeling Approach for Microwave Transistors
	Considering ElectrothermalAging Degradation  Lin Cheng, Hongliang Lu, Silu Yan, Junjun Qi, Jiantao Qiao, Yuming Zhang (Xidian University, China)
P2-50	0344: Electrical and Thermal Analysis of CNT nTSV Applied to BS-PDN: A Modeling Study
	Kai Ying, Baohui Xu, Jie Liang (Shanghai University, China)
P2-51	0357: A Unified Current-Voltage Compact Model for Organic Light-Emitting Diode
	Wenbin Wang, Mingyu Ma, Wangjun Yang, Jianghao Ma, Hailong You, Cong Li (Xidian University, China)
P2-52	0162: Threshold Voltage and Mobility Extraction of Negative Bias Temperature Instability in 22nm FD SOI MOSFETs
	Yibo Hu, Hao Ge, Zhipeng Ren, Yizhe Yin, Ruiyong Zhao, Jing Chen (Shanghai Institute of Microsystem and Information Technology, China)
P2-53	0428: Modeling of Silicon Single-Photon Avalanche Diodes for Process and Design Optimization
	Jing Fu, Anran Guo, Hongbo Zhang, Guowei Li, Huaping Ma,Ruizhi Li, Yuwei Chen (National Key Laboratory of Integrated Circuits and Microsystems, China; CETC No.44 Research Institute, China)
P2-54	0046: A Novel Modeling Method for BV Characteristics of ESD Protection Devices
	Ke Zhang, Yang Wang, Xiangliang Jin (Hunan Normal University, China; Peking University, China)

	Sharing Based on Analytical Model
	Yutao Zhang, Hongliang Lyu, Yuming Zhang, Ruxue Yao (Xidian University, China)
P2-56	0123: Research on the performance degeneration of GGNMOS under total
	ionizing dose Radiation
	Jiekai Feng, Ping Luo, Chengxin Li, Jiaxuan Hu, Peng Li, Pengfei Liao (Univ. of Elec.
	Sci. and Technol. Of China, China; Chongqing Institute of Microelectronics Industry
	Technology, China; The 24th Research Institute of China Electronics Technology
	Group Corporation, China)
P2-57	0208: The UIS Withstand Capability and Device Failure Mechanism of 650 V
	p-GaN Gate HEMTs
	Qihang Huang, Luanxi Ma, Shuting Huang, Yanning Nie, Jianggen Zhu, Yu Shi,
	Rongxin Du, David Zhou, Yuxi Wan, Bo Zhang, Qi Zhou (University of Electronic
	Science and Technology of China, China; Shenzhen Pinghu Laboratory, China)
	0100. Time Demanders District Description (1)
P2-58	0100: Time Dependent Dielectric Breakdown in n-MOSFETs Fabricated by
	Low-Temperature and Low-Pressure Mild Oxidation After Plasma Solidification
	Qiao Teng, Yanning Chen, Fang Liu, Bo Wu, Yongfeng Deng, Dawei Gao (Zhejiang
	University, China; Beijing Smart-chip Microelectronics Technology Co., Ltd, China)
	0228: Simulation of BTI for GAA MOSFETs with Enhanced Parameters
P2-59	Extraction
	Yongjia Wang, Yijiao Wang, Shuhan Wang, Jinghan Xu, Xiaoyan Liu (Peking
	University, China; Beihang University, China)
P2-60	0033: Gold Thermocompression Wafer Bonding for Quartz MEMS Applications
	Ting Yang, Dongxiang Han, Jun Xu, Tian-Ling Ren (Tsinghua University, China;
	Nanjing University of Aeronautics and Astronautics, China)
P2-61	0083: An Adaptive Threshold Analog Front-End Circuit for Direct ToF LiDAR
	Jianping Guo, Xiaoyang Zeng, Wenhong Li, Mingyu Wang (Fudan University, China)
P2-62	0184: Design of Ultra-Broadband Metamaterial Absorber from Infrared to
	Terahertz
	Xiangze Liu, Wenbin Zhou, Tiantian Shi, Yiming Liao, Feng Yan, Xiaoli Ji (Nanjing
	University, China; Nanjing University of Science and Technology, China)
	0398: Large modulation bandwidth Si-based avalanche photodiode for visible
P2-63	light communications
	Jiabin Wu, Yidi Hu, Chiang Zhu, Zhichong Wang, Xiaona Zhu, Chao Shen (Fudan
	University, China)
	Oniversity, Onina)
	0400: An artificial neuromuscular synapse based on a ferroelectric
P2-64	
	Pb(Zr <sub>1-x</sub> Ti <sub>x</sub> )O <sub>3</sub> /SiC floating gate transistor

Yu Liu, Lin Lin, Xiang Wang, Chengyan Zhong, Junxiong Guo, Wen Huang, Yufeng Guo (Nanjing University of Posts and Telecommunications, China; University of Electronic Science and Technology of China, China; Chengdu University, China)

# **Friday**

### Friday, October 25, 9: 00 – 10: 30

Thursday, October 25, 9: 00 – 10: 30

Grand Ball Room

**Keynote Session K4** 

Sheraton Zhuhai Hotel 1st Floor

Session Chair: Prof. Rui Yin, National Integrated Circuit Innovavtion Center, China

K4-1	CMOS Digital Radiography
9: 00	
~9: 45	Prof. Youngcheol Chae, Yonsei University, Korea
K4-2	High-Frequency and Wideband RF Filters for 6G and Wi-Fi 7
9: 45	Prof. Chengjie Zuo, University of Science and Technology of China, China
~10: 30	
	Coffee Break

#### Friday, October 25, 10: 45–12: 15

Friday, October 25, 10: 45 – 12: 15

Session A3: Digital & Memory Circuit

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Fan Ye, Fudan University, China

	Title
A3-1	0451: One-Step Circuit Analysis Based on LCA for Sparse Coding (invited)
10:45	Hanxi Xu, Zirui Chen, Qi Chen, Xiangshui Miao, Yuhui He (Huazhong University of
~11:15	Science and Technology, China; Politecnico di Milano, Italy)
A3-2	0369: A Hybrid-Logic Scheme for High-Performance and Low-Power Decoders
A3-2	in 7nm Process
11:15	Donghao Xia, Yuejun Zhang, Mengfan Xu, Liang Wen, Yiting Guo (Ningbo
~11:27	University, China; China Coast Guard Academy, China)
A3-3	0049: Ternary Logic Units Design Based on the TDDFETs
11:27	Hua Qiang, Haoran Lu, Xiaotao Liu, Linlin Xing, Bin Lu (Shanxi Normal University,
~11:39	China)
A3-4	0474: Enhancing SRAM Cell Stability Through Single-Carrier CMOS Latch
A3-4	Integration
11:39	Yuan-Yu Chuang, Pei-Zhang Xie, and Jyi-Tsong Lin (Sun Yat-Sen University, Taiwan,
~11:51	China)
A3-5	0199: A RRAM based 9T1R NVSRAM for Low-Power Computing in Memory
11:51	Huimeng Guo, Yujia Li, Tingrui Ren, Chenge Dong, Liang Wang, Yuanfu Zhao,
~12:03	Yanlong Zhang (Hangzhou Dianzi University, China; Beijing Microelectronics
712.03	Technology Institute, China; Beihang University, China)
A3-6	0377: A High-Resistance SOT Device Based Computing In-Memory Macro with
715-0	High Sensing Margin and Multi-Bit MAC Operations for AI Edge Inference
12:03	Junzhan Liu, Jinyao Mi, Haiyan Qin, He Zhang, Wang Kang (Beihang University,
~12:15	China; Hangzhou International Innovation Institute, China)

Friday, October 25, 10: 45 – 12: 15

Session B5: Mixed Signal II

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Fan Ye, Fudan University, China

	Title
B5-1	0167: When Time Interleaving encounters Oversampling in ADC (invited)
10:45	Mingqiang Guo, Dongyang Jiang, Shulin Zhao, Sai-Weng Sin, Rui P. Martins
~11:15	(University of Macau, Macao, China; Universidade de Lisboa, Portugal)

	L
B5-2	0322: A 0.000355mm <sup>2</sup> 4.6μm-Pitch 5.75fJ/Conv 6-bit SAR ADC for High
	Throughput Parallel Readout of Analog SRAM Computing-In-Memory
11:15	I' W I' I F II 'CI 7I ' 7I (V: II · · · CI · )
~11:30	Lin Wu, Lichen Feng, Hongwei Shan, Zhangming Zhu (Xidian University, China)
B5-3	0051: A 250MS/s, 12 Bit Pipeline-SAR ADC Using Coarse-fine Ring Amplifier
11:30	Lineles Lin Lauren Den Fen Ve (Feden Heimenster Chine)
~11:45	Linghao Liu, Junyan Ren, Fan Ye (Fudan University, China)
D5 4	0420: A 0.71pJ/b 16Gb/s Equalizer with Inverter_based CTLE and 4-Tap
B5-4	Speculative DFE
11:45	H.J. 71 Cl. V. I. D. W.J. I. (V.J. H Cl. )
~12:00	Huihong Zhang, Chuangao Yan, Luo Peng, Maliang Liu (Xidian University, China)
D5 5	0350: A Digital Foreground Calibration Method for Pipeline SAR ADCs Using
B5-5	Extended Kalman Filter
12:00	David They Views Views Don For Vo (Finder University China)
~12:15	Dayan Zhou, Yuguo Xiang, Junyan Ren, Fan Ye (Fudan University, China)

Friday, October 25, 10: 45 – 12: 15

Session C5: Sensor & MEMS II

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Zhanfeng Huang, Sun Yat-sen University, China

	Title
C5-1	0099: A Flexible Graphene Acoustic Sensor for Sound Signal Acquisition and
	Spike Neural Network Recognition
10:45	Lu-Yu Zhao, Hao-Yuan Shen, Yi-Wen Wu, Lu-Lu Zhang, Yu-Tao Li, Tian-Ling Ren
~11:00	(Beijing Institute of Technology, China; Beijing University of Chemical Technology,
771.00	China; Tsinghua University, China)
C5-2	0058: 0.15μm BCD Platform with High Sensitivity Hall Device and Low Noise
C3-2	CMOS for Sensor IC Applications
11:00	Guiqiang Zheng, Qingyin Zhong, Jie Ma, Nannan Cheng, Yichen Li, Yongjia Li,
~11:15	Siyang Liu, Xiaofeng Sun, Dejin Wang, Sen Zhang, Long Zhang, Weifeng Sun
~11.13	(Southeast University, China; CSMC Technologies Corporation, China)
C5-3	0166: A High Dynamic Range Pixel with Inverse Proportional Response
11:15	Vyskan Wang Wanii Ma Hagning Cyn Lingiing Liv (Cyn Vat gan Hainguit, Ching)
~11:30	Yuchen Wang, Wenji Mo, Haoning Sun, Jingjing Liu (Sun Yat-sen University, China)
C5-4	0285: Enhancement of Image Sensor Pixel Performance through Ring-Shaped
C3-4	Vertical Transfer Gate Structure
11:30	Shuang Yan, Shuai Yuan, Haoping Zheng, Yudi Zhao, Gang Du, Junchen Dong, Kai
~11:45	Zhao (Beijing Information Science and Technology University, China; Peking

University, China; HT-tech Jiangsu Co., Ltd., China)

Friday, October 25, 10: 45 – 12: 15 **Session D5: Process I**Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor **Session Chair:** Prof. Heng Wu, Peking University, China

	Title
D5-1	0251: Studies on Selective Deposition of SiO <sub>2</sub> by Rapid Atomic Layer Deposition
	(Invited)
10:45	Sicong Shao, Jin Yan, Wang Li, Kun Cao, Rong Chen (Huazhong University of
~11:15	Science and Technology, China)
D5-2	0404: Resistance Dependence of Cobalt on Line Width in Advanced
D5-2	Interconnects: First-Principles Modelling
11:15	W W M 1' H Cl' Cl (E l H: ', Cl' )
~11:30	Kang Wang, Menglin Huang, Shiyou Chen (Fudan University, China)
	0418: Reducation of Specific Contact Resistivity by Employing
<b>D5-3</b>	Pre-amorphization Implantation and In situ Steam Generation Oxidation
	Chang Liu, Xu Chen, Jinbiao Liu, Yanping He, Wenjuan Xiong, Weibing Liu,
11:30	Mingshan Liu, Zhe Liu, Yaoqi Dong, Jeffrey Xu, Jing Xu, Jun Luo (Institute of
~11:45	Microelectronics, Chinese Academy of Sciences, China. University of Chinese
	Academy of Sciences, China. Huawei Technologies Company limited, China)
	0432: High-performance Ultrathin ITO Thin Film Transistor With Ultralow
D5-4	Subthreshold Swing
11:45	
~12:00	Yanheng Liu, Tiaoyang Li (Fuzhou University, China)

Friday, October 25, 10: 45 – 12: 15

Session E5: Reliability I

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Ming Xiao, Sun Yat-sen University, China

	Title
D5 1	0453: Challenges of Design for Reliability in Advanced CMOS Technology:
E5-1	From Single-mode to Mixed-mode Mechanisms (invited)
10:45	Zimon Com Linia Zhao Paulana Panda Wan (Dakin Hairania China)
~11:15	Zixuan Sun, Lining Zhang, Ru Huang, Runsheng Wang (Peking University, China)
E5-2	0232: Frequency-dependent Time-dependent Dielectric Breakdown (TDDB)
E5-2	Behavior and Physical Study in Gate Oxides (invited)
11:15	Wei Liu, Chu Yan, Xinwei Yu, Yiming Qu, Wenchao Yan, Yi Zhao (Zhejiang

~11:45	University, China; East China Normal University, China; Zhejiang Li-ryder
	Technologies Co. LTD, China)
D5.3	0181: Lightning Protection Stacked TVS Structure Based on a Novel
E5-3	Total-Ionizing-Dose Radiation-hardened Technology
11 45	Zhao Qi, Hongquan Chen, Yirui Jia, Nailong He, Zhili Zhang, Sen Zhang, Ming Qiao,
11:45 ~12:00	Bo Zhang (University of Electronic Science and Technology of China, China; CSMC
~12:00	Technologies Corporation, China)

Friday, October 25, 10: 15 – 12: 15

Session F5: Device Modeling I

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Ming Li, Peking University, China

Title
0466: Electric-Thermal Characteristics of Bottom P-i-N Isolated Nanosheet
Gate-All-Around FETs (invited)
Chunlei Wu, Hanzhi Gu, Jian Ma, Boqian Shen, Fei Zhao, Yueyuan Yu, Yiming Xia,
Qingqing Sun, David Wei Zhang (Fudan University, China; Shanghai Integrated
Menufacturing Innovation Center Co., Ltd, China; Jiashan Fudan Institute, China)
0180: Surface Potential-Based Compact Model for ITO Thin-film Transistors
with Ultra-thin Channel
Wenting Xu, Xinxin Shen, Zuoxu Yu, Tingrui Huang, Yuzhen Zhang, Weifeng Sun,
Wangran Wu (Southeast University, China)
0186: A Continuous Full Channel Potential Model for Accurate Synthetic
Electricfield Calculating in Gate-All-Around Devices
Fei Zhao, Chunlei Wu, Yumin Xu, Boqian Shen, Jian Ma, Hanzhi Gu, Yueyuan Yu,
Yiming Xia, Qingqing Sun, David Wei Zhang (Fudan University, China; Shanghai
Integrated Manufacturing Innovation Center Co., Ltd, China; Jiashan Fudan Institute,
China)
0271: Deep Learning and Adaptive Pattern Search Based BSIM-CMG Parameter
Extraction Applicable to Process Migration
Xingyu Li, Wangyong Chen, Linlin Cai (Sun Yat-sen University, China)

## Friday, October 25, 13: 30 – 15: 15

Friday, October 25, 13: 30 – 15: 15

Session A4: Processor

Meeting Room 1

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Yao Liu, Sun Yat-sen University, China

	Title
A4-1	0201: RISC-V Domain-Specific Processor for Accelerating SPHINCS+ on
	Multi-Core Architecture
13:30	
~13:45	Shengnan Zhang, Yifan Zhao, Xinglong Yu, Jun Han (Fudan University, China)
A4-2	0113: Design of an Out-of-Order Superscalar Processor with Improved Register
A4-2	Alias Table Recovery Method
13:45	Wu Yang, Jun Zhang (Central South University, China)
~14:00	wu Tang, Jun Zhang (Centrut South University, China)
A4-3	0220: An SDPF RISC-V Processor with Two-stage Pseudo-pipelined Architecture
A4-3	for IoT Applications
14:00	Wenji Mo, Yuchen Wang, Haoning Sun, Jingjing Liu (Sun Yat-sen University, China)
~14:15	wenji wo, Tuenen wang, Haoning Sun, Jingjing Liu (Sun Tui-sen University, China)
A4-4	0366: A Unified Verification Scheme for the Acceleration of RISC-V Processor
A4-4	Design
14:15	Zixiang Chen, Jiyuan Bai, Yueru Yu, Gengsheng Chen, Xiaofang Zhou (Fudan
~14:30	University, China; Jiashan Fudan Institute, Jiaxing, China)
A4-5	0370: Asynchronous Arbitration Circuit Optimization for Multicore
A4-3	Neuromorphic Processors
14:30	Jiajie Guo, Guangyao Lin, Bohan Wang, Zhiyi Yu, Shanlin Xiao (Sun Yat-sen
~14:45	University, China)

Friday, October 25, 13: 30 – 15: 15

Session B6: Mixed Signal III

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Shuo Li, Fudan University, China

	Title
B6-1	0289: A Second-Order Charge Pump Noise-Shaping SAR ADC (invited)
13:30	Haoning Sun, Yuchen Wang, Wenji Mo, Kangkang Sun, Jingjing Liu (Sun Yat-Sen
~14:00	University, China)
D.( 2	0385: Computing in Memory for Accelerating Light Weighted On-Chip Learning
B6-2	in IoT Devices (Invited)
14:00	Zhiwang Guo, Xiaoyong Xue, Jun Han, Peng Zhou, Xiaoyang Zeng (Fudan
~14:30	University, China; Shaoxin Laboratory, China)
B6-3	0314: A Novel Beamforing Receiver Archiercture Combining MASH SDM and
	BSP
14:30	Tao Zhong, Yuekang Guo, Jing Jin, Jianjun Zhou (Shanghai Jiao Tong University,

~14:45	China)

Friday, October 25, 13: 30 – 15: 15

Session C6: RF Circuit II Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor Session Chair: Prof. Yun Wang, Fudan University, China

Title
0424: A 10-GHz Low Power Class-C VCO with Long-Term Reliability and
Tunable Performance in 28 nm FD-SOI for Satellite Communications (invited)
Yann Deval, Henrique Iha Taguti, Ayoub Ait Ihda, Herve Lapuyade, Stephane
Rochette, Francois Rivet (Univ. Bordeaux, France; Thales Alenia Space, France)
0313: A 191-GHz Harmonic Oscillator with Self-Feeding Line and Return-Path
Gap Coupler Structure in 65nm CMOS
Xiaohan Shen, Chen Jiang (Fudan University, China)
0278: A Blocker-Tolerant High-Linear Receiver Employing Baseband
Noise-Cancelling and Bottom-Plate Switched-Capacitor Techniques
Chenxiang Cai, Gengzhen Qi (Sun Yat-sen University, China)
0412: A High Sensitivity Series-Parallel Rectifier with Pre-Bias for RF Energy
Harvesting Systems
HaiQin Wu, Dejian Li, Xin Jin, Xufeng Liao, Lianxi Liu (Xidian University, China;
Beijing Smart-Chip Microelectronic Technology Co., Ltd, China)
0103: A 24.3-43.7 GHz Variable-Gain Low-Noise Amplifier With Phase Self-Compensation
Yue Wu, Wei Li, Mohan Zhou, Hongtao Xu (Fudan University, China)
0480: A Broadband Active Variable Attenuator With Phase Compensation Technique
Zhiying Xia, Zhiqun Li, Bofan Chen, Xiaowei Wang (Southeast University, China)

Friday, October 25, 13: 30 – 15: 15

Session D6: Process II

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Xiaona Zhu, Fudan University, China

Prof. Fan Ye, Fudan University, China

Title
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D6-1	0456:Advanced Logic Devices' DTCO Beyond 3nm Process Technology Node (invited)
13:30	Xiaona Zhu, Hongliang Lu, Shaofeng Yu, David Wei Zhang (Fudan University,
~14:00	China)
D( 1	0454: A Modified Virtual-Source Model for Ballistic Transport Characterization
D6-2	of FinFETs at Cryogenic Temperature
14:00	Hongbo Wang, Zirui Wang, Zixuan Sun, Runsheng Wang, Ru Huang (Peking
~14:15	University, China)
D6-3	0114: Investigation on Asymmetric HfO <sub>2</sub> -ZrO <sub>2</sub> -HfO <sub>2</sub> Superlattice Gate Stacks
D0-3	with Ultra-low EOT for Advanced Transistors
14:15	Haiyuan Lyu, Kun Zhong, Zhaohao Zhang, Huaxiang Yin (Institute of
~14:30	Microelectronics, Chinese Academy of Sciences, China; University of Chinese
~14.30	Academy of Sciences, China)
D6-4	0119: Evaluation of Contact Resistance with the 'L' Kelvin Test Structure and the
D0-4	Modified Kelvin Test Structure
14:30	Gui Chan Vun Haa Shaa Vin Ding Ou (Fudge University Ching)
~14:45	Gui Chen, Yun-Hao Shao, Xin-Ping Qu (Fudan University, China)

Friday, October 25, 13: 30 – 15: 15

Session E6: Reliability II

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Wangyong Chen, Sun Yat-sen University, China

	Title
E.C. 1	0221: Characterization and Modeling of Non-conducting RF Hot Carrier Stress
E6-1	in FinFETs (invited)
13:30	G. Niu, X. Ding, H. Zhang, W. Wang, K. Imura, F. Dai (Auburn University, USA;
~14:00	Maxlinear Inc., USA)
E6-2	0164:Predictive Modelling of Hot Carrier Degradation (invited)
	James Brown, Kean Hong Tok, Rui Gao, Zhigang Ji, Weidong Zhang, Jian Fu
14:00	Zhang (Liverpool John Moores University, UK; No. 5 Electronics Research Institute of
~14:30	the Ministry of Industry and Information Technology, China; Shanghai Jiaotong
	University, China)
E6-3	0142: New Insights into the Saturation Behavior of the Hot Carrier Degradation
E0-3	in STI-based N-type LDMOS
14:30	Zhuaging Vu Dan Caa Vangshang Sun Junlin Huang (Higiliaan Ching)
~14:45	Zhuoqing Yu, Dan Gao, Yongsheng Sun, Junlin Huang (Hisilicon, China)
E6-4	0081: The TID Response and HCI Degradation for multi-Vt nFinFETs
14:45	Ruxue Yao, Hongliang Lu, Yuming Zhang, Yutao Zhang (Xidian University, China)

~15:00	

Friday, October 25, 13: 30 – 15: 15

Session F6: Device Modeling II

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Xiaoyan Liu, Peking University, China

	Title
F6-1	0059: Vertical Channel Transistor (VCT) for Advanced Logic and Memory
	Applications (invited)
13:30	Mingmin Shi, Ran Bi, Ming Li (Peking University, China; Beijing Advanced
~14:00	Innovation Center for Integrated Circuits, China)
F6-2	0423: High Precision I-V Characteristics SPICE Model for Silicon Carbide MOSFET
14:00 ~14:15	Jinhong Shi, Yongxi Li, Jincheng Shi, Ruguan Li, Haimeng Huang, Hongqiang Yang (University of Electronic Science and Technology of China, China; GRG Metrology & Test Group Co., Ltd., China)
F6-3	0440: An Analytical Model for Characterizing Density of States of Oxide Transistors
14:15 ~14:30	Siyuan Hu, Chuanlin Sun, Junchen Dong, Zhensong Li, Kai Zhao, Dedong Han, Xing Zhang (Peking University, China; Beijing Information Science & Technology University, China; Peking University Shenzhen Graduate School, China)
F6-4	0225: A Physics-Informed Neural Network Model for Body Potential Distribution in MOSFETs down to 50 K
14:30	Honglin Wu, Fangxing Zhang, Xinyue Zhang, Baokang Peng, Wu Dai, Lining Zhang,
~14:45	Runsheng Wang, Ru Huang (Peking University, China)

### Friday, October 25, 15: 30 – 17: 15

Friday, October 25, 15: 30 – 17: 15

Session A5: FPGA Based Design

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor

Session Chair: Prof. Mingyu Wang, Sun Yat-sen University, China

	Title
A5-1	0207: A Run-time Temperature Monitoring with Adaptive Duty Cycle Control for
	FPGA Applications
15:30	Weizhi Li, Wangyong Chen, Haifeng Chen, Haoyu Zhang, Linlin Cai (Sun Yat-sen
~15:45	University, China)
A5-2	0118: An FPGA-Based Top-K Gradient Compression Accelerator for Distributed

	Deep Learning Training
15.45	Ziyao Wang, Jiayu Zhang, Kunyue Li, Jialei Sun, Feng Dong, Ke Chen, Yong Qiao,
15:45 ~16:00	Jianfei Jiang (National Key Laboratory of Advanced Micro and Nano Manufacture
~16:00	Technology, China; Beijing iQlYI Science & Technology Co Ltd, China)
A5-3	0258: Dynamic-Matrix-Encryption Based Secure Strong PUF for Device
1100	Authentication Protocols
16:00	Liangxiao Zhao, Gang Li, Pengjun Wang, Xuejiao Ma, Ziyu Zhou (Wenzhou
~16:15	University, China; Wenzhou University of Technology, China; Ningbo University,
10.15	China)
A5-4	0240: A Low Latency and High Throughout Hardware Design of Random Matrix
110 1	Number Generator for FrodoKEM
16:15	Shengfei Gu, Jiahao Lu, Tianze Huang, Jiaming Zhang, Kai Li, Cheng Wu, Mingbo
~16:30	Wang, Xianqi Mei, Ang Hu, Dongsheng Liu (Huazhong University of Science and
10.50	Technology, China; JinYinHu Laboratory, China)
A5-5	0465: A 4K60fps Ultra-Low-Latency Light Compression Encoder for
1 5 0 0	Bandwidth-Constrained Scenarios
16:30	Yanzhong Li, Leilei Huang, Yibo Fan (Fudan University, China; East China Normal
~16:45	University, China)
A5-6	0086: Layer Pipelined Neural Network Accelerator Design on 2.5D FPGAs
16:45	M W Cl W (E 1 H : : : Cl: )
~17:00	Mengxuan Wang, Chang Wu (Fudan University, China)
A5-7	0237: Fast and Accurate Partial-Zoom Depth Estimation for SPAD LiDAR
	Readout on FPGA
17:00	Lichen Feng, Hongwei Shan, Rundong Cai, Zhangming Zhu (Xidian University,
~17:15	China)

Friday, October 25, 15: 30 – 17: 15

Session B7: Chip Test

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Shuo Li, Fudan University, China

	Title
B7-1	0135: In Situ Localization Techniques of Defects in Advanced Semiconductor
	Devices from Macroscale to Atomistic-scale (invited)
15:30	Jialu Huang, Jingming Zhou, Zuoyuan Dong, Runsheng Wang, Junhao Chu, Xing Wu
~16:00	(East China Normal University, China; Peking University, China)
B7-2	0402: Wafer-Level Characterization of Ring-Oscillators Frequency Degradation
	in FinFET Technology
16:00	Hao Chang, Dan Gao, Yongsheng Sun, Junlin Huang (Hisilicon Technologies Co.,

~16:15	LTD, China)
B7-3	0246: Exhaustive Application-Dependent Testing for FPGA Interconnect
D/-3	Resources
16:15	Wenwei Chen, Xinyu He, Tongshu Ding, Jian Wang, Jinmei Lai (Fudan University,
~16:30	China)
B7-4	0303: A Comprehensive and Efficient Instruction-level Testing Method for
D/-4	Processor
16:30	Zixin Yang, Zhichao Wei, Huanlin Luo, Jian Wang, Jinmei Lai
~16:45	(Fudan University, China; Shanghai Academy of Spaceflight Technology, China)
B7-5	0006: Thermal Effect and Calibration for High Precision On-Wafer Analog IC
<b>D</b> 7-3	Probe Testing
	Daisuke Iimori, Takayuki Nakatani, Shogo Katayama, Gaku Ogihara, Shuhei
	Yamamoto, Misaki Takagi, Yujie Zhao, Jianglin Wei, Anna Kuwana, Keno Sato,
16:45	Takashi Ishida, Toshiyuki Okamoto, Tamotsu Ichikawa, Kentaroh Katoh, Kazumi
~17:00	Hatayama, Haruo Kobayashi (Gunma University, Japan; Shenyang University of
	Chemical Technology, China; Yibin University, China; ROHM Semiconductor, Japan;
	Fukuoka University, Japan)

Friday, October 25, 15: 30 – 17: 15

Session C7: Sensor & MEMS III

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Zhanfeng Huang, Sun Yat-sen University, China

<b>0460: Waterproof and Wearable Power Sources (invited)</b> Sixing Xiong; Kenjiro Fukuda, Takao Someya (RIKEN, Japan; The University of Tokyo, Japan)
Tokvo, Japan)
- V - L - /
0146: A CMOS Pixel Sensor for Precise Track and Charge Measurement of Cosmic Ray Nuclei
Ruikai Zhang, Wen He, Shanqiang Yang, Min Luo, Chenxu Wang, Cunfeng Feng, Meng Wang, Liang Zhang, Anqing Wang, Jianing Dong, Dong Liu, Yan Niu, Yang Zhou, Yuehong Gong, Xiaoli Wang, Shucheng Shi (Harbin Institute of Technology, China; Shandong University, China; Institute of High Energy Physics Chinese
Academy of Sciences, China; ShanDong JiaoTong University, China)
0429: Sc0.096Al0.904N-Based Bimorph Piezoelectric Micro Machined Ultrasonic
Transducers
Ziye Zhai, Wenjuan Liu, Chengliang Sun (Wuhan University, China)

Friday, October 25, 15: 30 – 17: 15 **Session D7: 3D Integration**Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor **Session Chair:** Prof. Ming Li, Peking University, China

Title
0283: HISIM: Design Exploration of 2.5D/3D Heterogeneous Integration for AI
Computing (Invited)
Zhenyu Wang, Pragnya Sudershan Nalla, Jingbo Sun, A. Alper Goksoy, Sumit K.
Mandal, Jae-sun Seo, Vidya A. Chhabria, Jeff Zhang, Chaitali Chakrabarti, Umit Y.
Ogras, Yu Cao (Arizona State University, USA; University of Minnesota, USA;
University of Wisconsin-Madison, USA; Indian Institute of Science, India; Cornell
Tech, USA)
Analysis of Current Status and Trends in Microsystem Integration Technology
Based on TSV Advanced Packaging (Invited)
Hua Yao (Natural-Integration Advanced Semiconductor Technology Co., Ltd., China)
0431: Flip 3D (F3D): A Novel 3D Integration Technology with Dual-side
Integration Capabilities (invited)
Heng Wu, Haoran Lu, Runsheng Wang, Ming Li, Yibo Lin, Weihai Bu, Jin Kang, Ru
Huang (Peking University, China)
0035: Modeling and Simulation of A Conical 3D Monopole Antenna Embedded in
Substrate for WNoC
Junhao Wang, Ziyu Liu, Zhiyuan Zhu, Lin Chen, Qingqing Sun, Wei David Zhang
(Southwest University, China; Fudan University, China; Jiashan Fudan Institute,
China)

Friday, October 25, 15: 30 – 17: 15 **Session E7: Reliability III**Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor **Session Chair:** Prof. Zhigang Ji, Shanghai Jiaotong University, China

	Title
E7-1	0463: Modeling and Parameter Extraction of Semiconductor Devices for
	Simulation and Design Optimization of ESD Protection Circuits on BCD
	Technologies for Automobile and Industry Applications (invited)
15:30	Yuhua Cheng, Wei-wei Yu, Eugene Worley (Peking University, China; Silicon
~16:00	Crossing, LLC, USA)
E7-2	0224: A Novel Double-zener Process and Multiplex Design for High-power Surge
	and High-speed ESD Devices Development
16:00	Zhao Qi, YiRui Jia, Hongquan Chen, Ming Qiao, Zhaoji Li, Bo Zhang (University of
~16:15	Electronic Science and Technology of China (UESTC), China;)

E7-3	0206: The non-monotonic instability of VTH and Rds,on in P-GaN Gate HEMTs Under Repetitive Short Circuit Stress: The role of electric-field & selfheating effect
16:15 ~16:30	Long Wang, Ning Yang, Shuting Huang, Jianggen Zhu, Kuangli Chen, Chao Feng, Haolin Hu, Wei Zeng, David Zhou, Yuxi Wan, Bo Zhang, and Qi Zhou (University of Electronic Science and Technology of China (UESTC), China; Shenzhen Pinghu Laboratory, China)

Friday, October 25, 15: 30 – 17: 15

Session F7: Device Modeling III

Sheraton Zhuhai Hotel 2<sup>nd</sup> Floor
Session Chair: Prof. Chunlei Wu, Fudan University, China

	Title
F7-1	0448: Neural Network Assisted Mosfets Model Development (invited)
15:30	Viceyon Lin (Paking University Ching)
~16:00	Xiaoyan Liu (Peking University, China)
F7-2	0421:Modeling the Transient Characteristics with Trap Behaviors in LTPS-TFTs
16:00	Haolin Li, Zheng Zhou, Xiaoyan Liu (Peking University, China; Beijing Advanced
~16:15	Innovation Center for Integrated Circuits, China)
E7 2	0277: A Novel β-Ga <sub>2</sub> O <sub>3</sub> -Based Enhancement-Mode Transistor Combining
F7-3	Heterojunction Gate and Fin shaped Gate
16:15	Yu Shao, Yunlong He, Xiaoli Lu, Songyao Wang, Xuefeng Zheng, Xiaohua Ma, Yue
~16:30	Hao (Xidian University, China)
F7-4	0358: Electrical Characteristics and Thermal Reliability Investigation of
F /-4	TreeFET, FishboneFET, CombLikeFET and NSFET
16:30	Mingyu Ma, Wenbin Wang, Haokun Li, Shujun Gao, Hailong You, Cong Li (Xidian
~16:45	University, China)